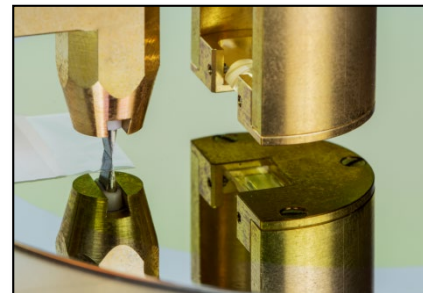
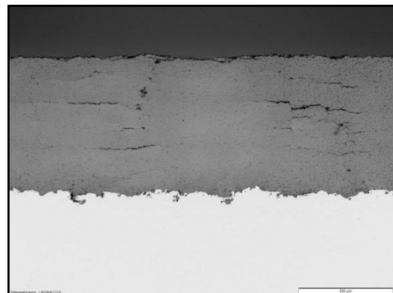
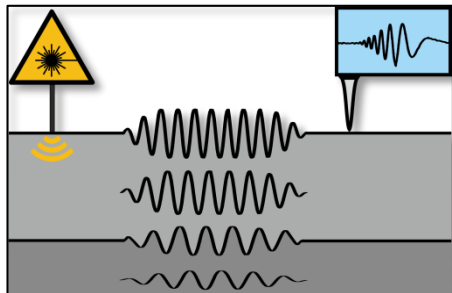
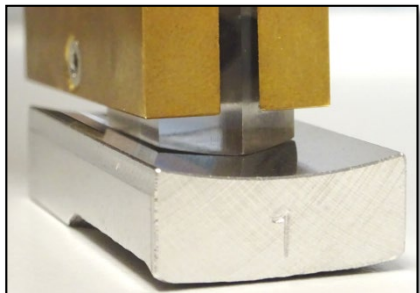
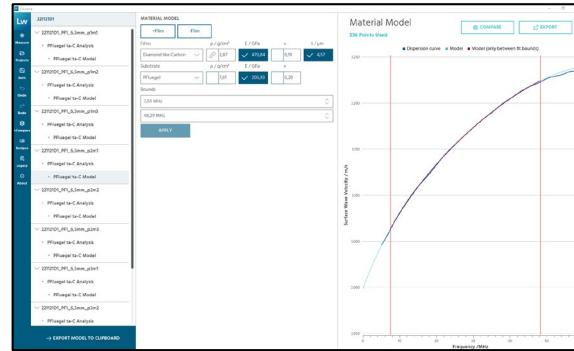
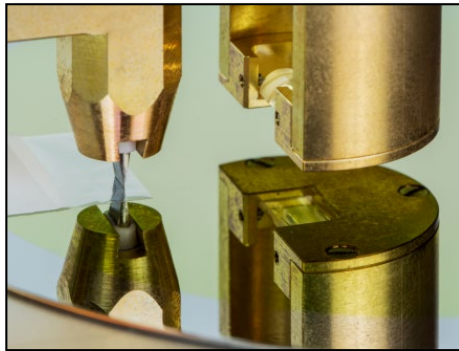


LWave – Non-destructive characterization of coatings and material surfaces by laser-induced surface acoustic wave spectroscopy

Fraunhofer Institute for Material and Beam Technology IWS, Germany



LWave – at a glance



LWave – Our one-of-a-kind measurement technology offers

- Access to surface material properties: Non-destructive, quick with highest accuracy
- For academia: unique research options for material science and solid state physics
- For industry: Easy quantification of surface properties in less than one minute
- Custom solutions for research, quality control, analysis and automation
- Fully integrated software for measurement and analysis

Facts and numbers

Complies with EN 15042-1:2006
30+ systems world wide
30+ years of experience
70+ peer reviewed contributions
2000+ citations
R&D 100 award

Contents

Introduction

Application Overview and How it works

Method

Measurement Principle, Evaluation Concepts, Material Models

Development and Background

Development, History

Case Studies

Semiconductor, PVD, Thermal Spray, Laser Cladding, Surface treatment, Comparison with Indentation, ...

Methodical Aspects

Roughness, Sample curvature, Comparison with Nanoindentation

Worldwide Contact

Introduction

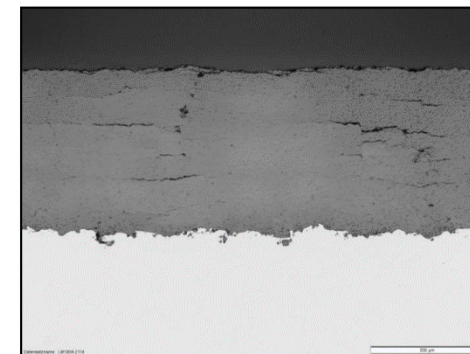
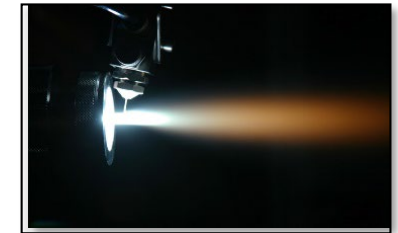
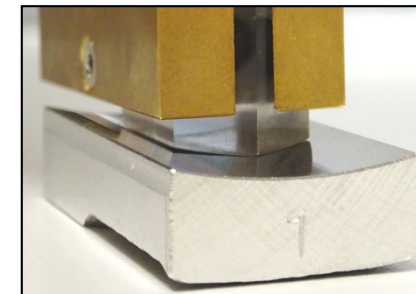
Components and technologies

Mechanical properties of coated components


- Cylinder liner coatings (APS, wire arc spraying, ...)
- Electric heaters (thermal sprayed coatings)
- Brake disk coatings (laser cladding)
- Heavy duty gear parts (cemented carbide coatings)
- 3D-printed metal components (SLM)
- Piston pins, tappets, chain components (PVD)
- And many more....

For R&D and quality control

- Effective Modulus (Pores, cracks, voids, delamination)
- Thickness
- Homogeneity
- Fast and effective – high throughput screening

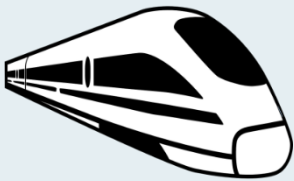


Highlights



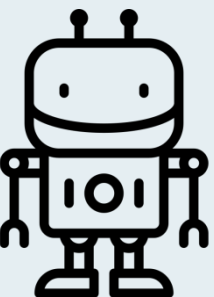
non-destructive

John Caserta, CC BY 3.0



fast
(< 60 s)

www.Pixabay.com Free Licence



fully automatable

Freepik, CC BY 3.0

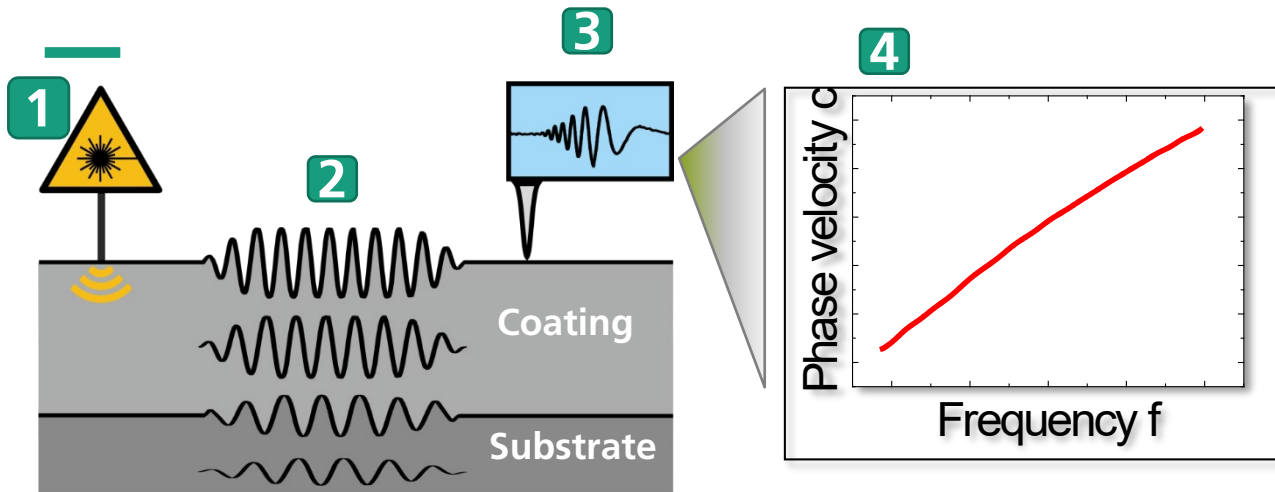
Basics

- LAwave® - Laser-induced surface acoustic waves spectroscopy
- Can access mechanical properties of coatings and surfaces
 - Integral and effective mechanical information
 - including pores, cracks and delamination
- Numerous applications for industrial quality control and R&D

Advantages over indentation

- Faster measurement, no calibration, less consumables
- Higher precision, more and integral information
- Measures on rough surfaces
- True effective modulus: no plastic deformation, no compression of cracks, pores and defects

How it works - Overview



- (1) Broadband surface acoustic waves (SAW) induced by short laser pulses
- (2) SAW propagation, velocity depends on frequency
- (3) SAW measurement: piezoelectric element → digitizing oscilloscope

- (4) Fourier transformation yields velocity over frequency (dispersion curve)
- (5) Dispersion curve analysis using different evaluation strategies

5

Material model

film 4:	E_4, ν_4, ρ_4, d_4
film 3:	E_3, ν_3, ρ_3, d_3
film 2:	E_2, ν_2, ρ_2, d_2
film 1:	E_1, ν_1, ρ_1, d_1
substrate	isotropic: E, ν, ρ

Calibration data

Ok/not ok boundaries

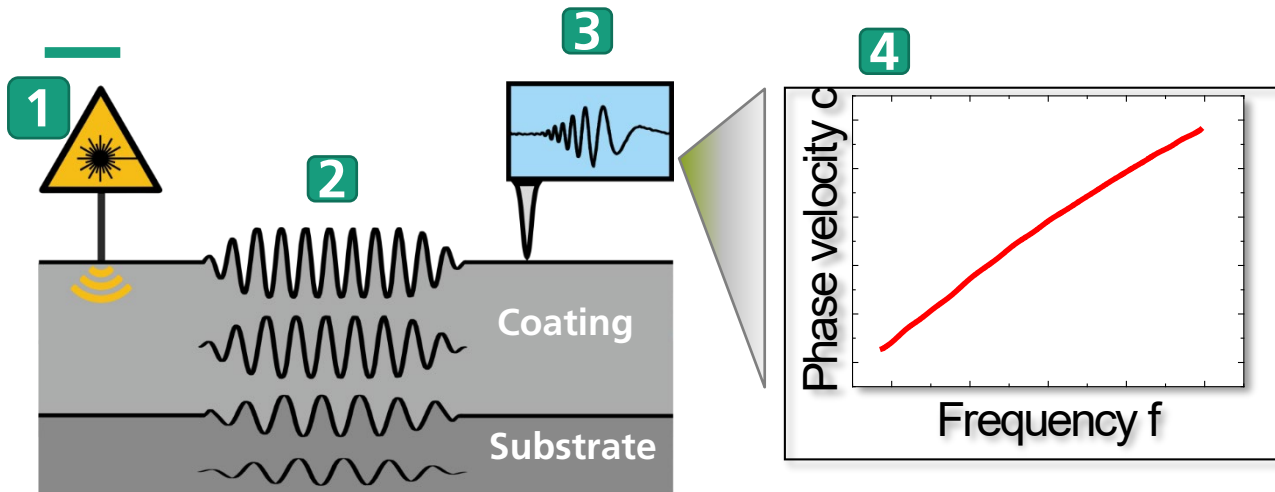
Possible results

- Young's Modulus
 - Density
 - Depth of: Nitriding layer, Case-hardening, Damage layers
 - Porosity, crack density
 - Delamination
 - Build-up structure
 - Surface hardness
- Anything that affects your mechanical integrity of the material



Method

Method Overview



- (1) Surface acoustic wave (SAW) generation
- (2) SAW propagation through measured material volume
- (3) SAW measurement by piezoelectric element

- (4) Calculation phase velocity over frequency (dispersion curve)
- (5) Different analysis strategies

5

Material model

film 4:	E_4, ν_4, ρ_4, d_4
film 3:	E_3, ν_3, ρ_3, d_3
film 2:	E_2, ν_2, ρ_2, d_2
film 1:	E_1, ν_1, ρ_1, d_1
substrate	isotropic: E, ν, ρ

Calibration data

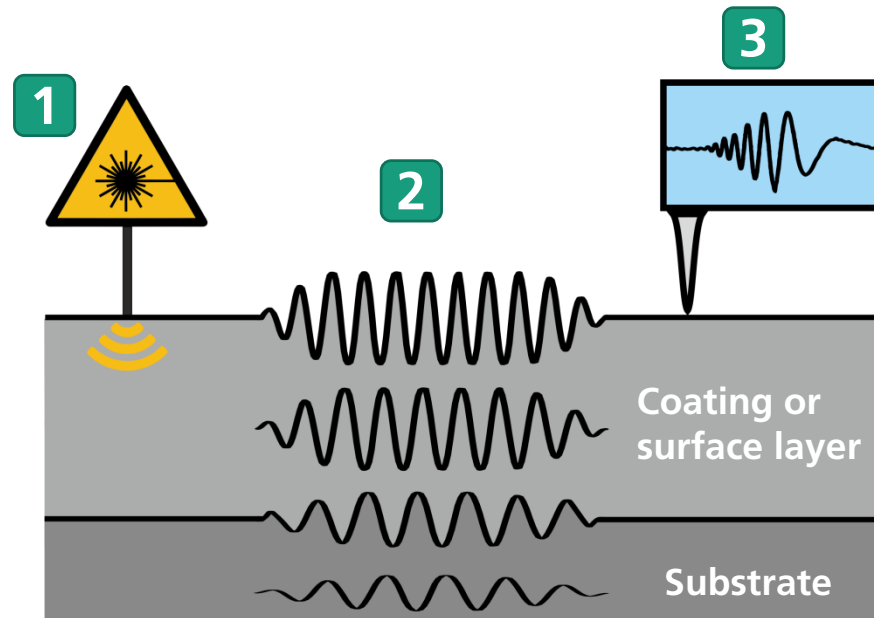
Ok/not ok boundaries

Possible results

- Young's Modulus
- Density
- Depth of: Nitriding layer, Case-hardening, Damage layers
- Porosity, crack density
- Delamination
- Build-up structure
- Surface hardness

.... Anything that affects your mechanical integrity of the material

Surface wave excitation and measurement



1 SAW excitation

- Broadband surface acoustic waves (SAW) induced by short laser pulses

2 SAW propagation

- Penetration depth of SAW \approx wavelength
- SAW velocity c depends on frequency f

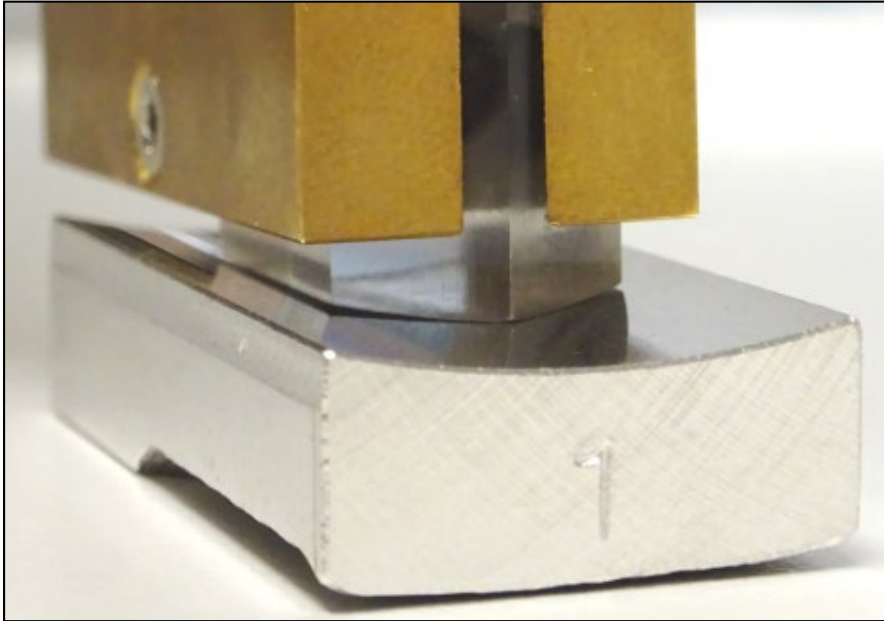
$$\lambda = c/f$$

$$c = c(f)$$

3 SAW detection

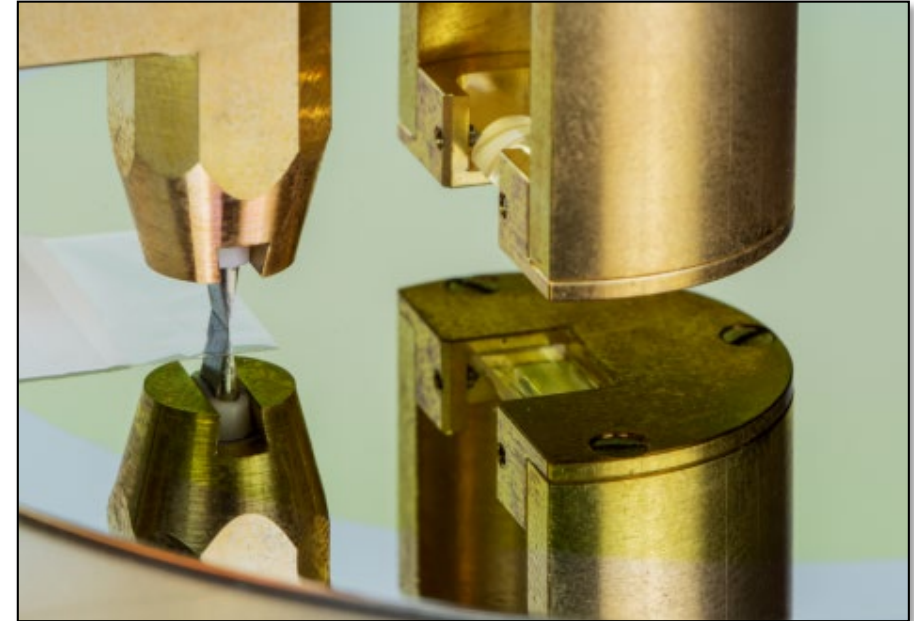
- Mechanical vibrations \rightarrow electrical signals
 - Wedge type sensor with piezoelectric foil for 20-250 MHz
 - Conventional ultra sound sensor for 1-20 MHz
- Oscilloscope measures impulse run-time

Sensors



Low frequency

- 1-20 MHz, 20-500 μm thickness
- Thermal spray, laser cladding, surface hardening

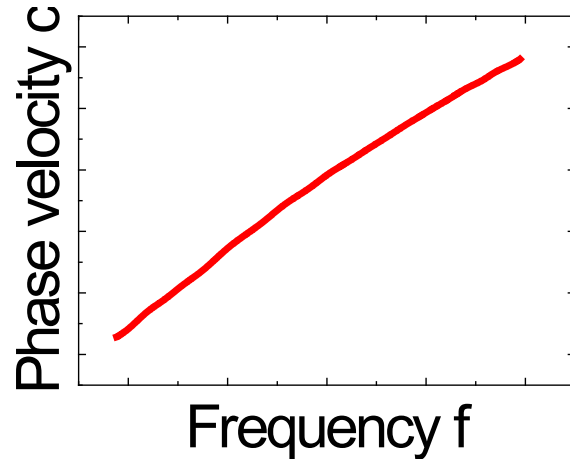


High frequency

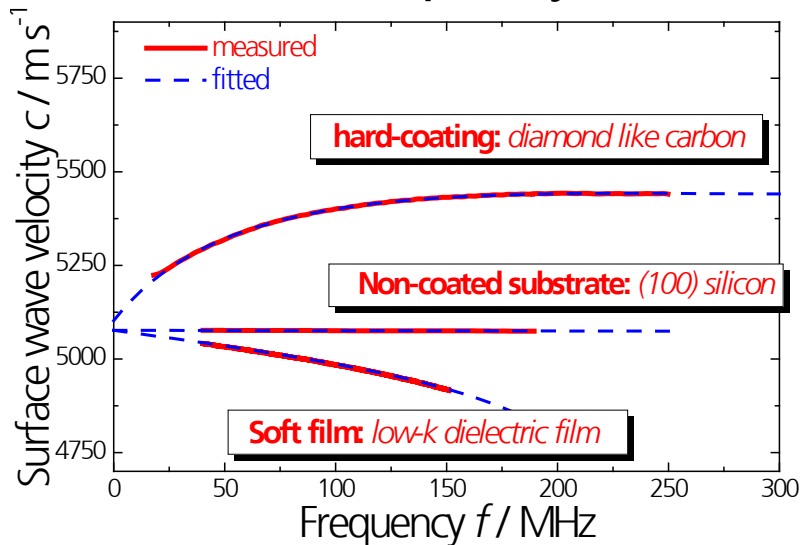
- 20-250+ MHz, ~ nanometers to 20 μm
- PVD, CVD

Evaluation of Measurement

4



5



4 Measuring procedure and data analysis

- Variation of propagation distance x
 - FT of the detected signals
- Phase spectra $\Phi(f)$ for different distances and phase velocity $c(f)$

$$c(f) = \frac{(x_2 - x_1)2\pi f}{\Phi_2(f) - \Phi_1(f)} = \text{dispersion curve}$$

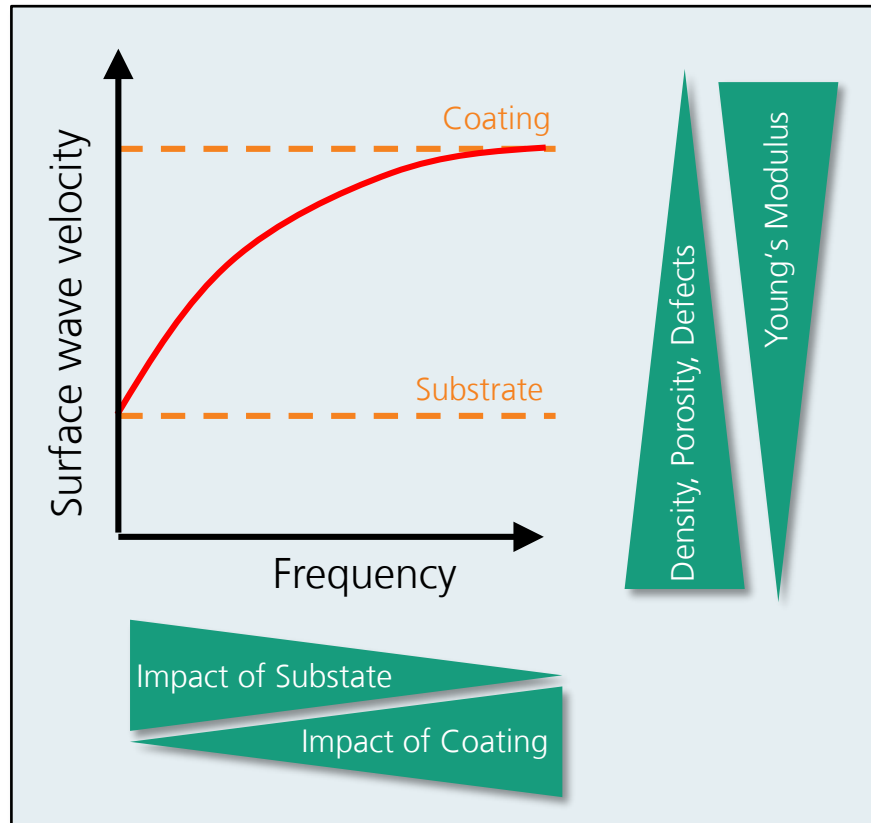
- Shape of the dispersion curve $c(f)$ depends on elasticity, density and film thickness

5 Approaches to get film properties

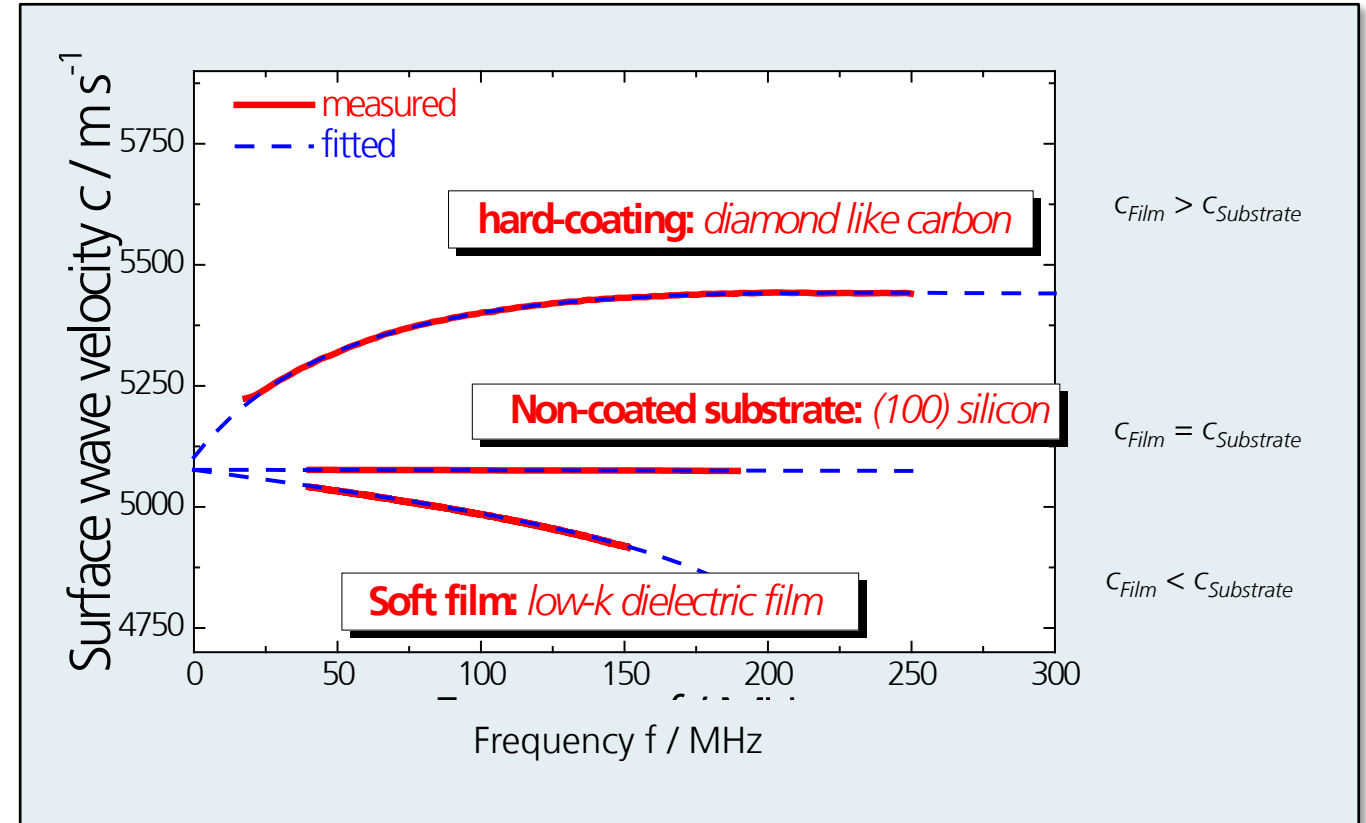
- Fitting measured curve to theory, using a material model
- Calibration with another method
- Defining ok/not ok boundaries from known samples
- Using regression fitting and KI with know samples

Dispersion Curve – Influence of Material System

Schematic influence



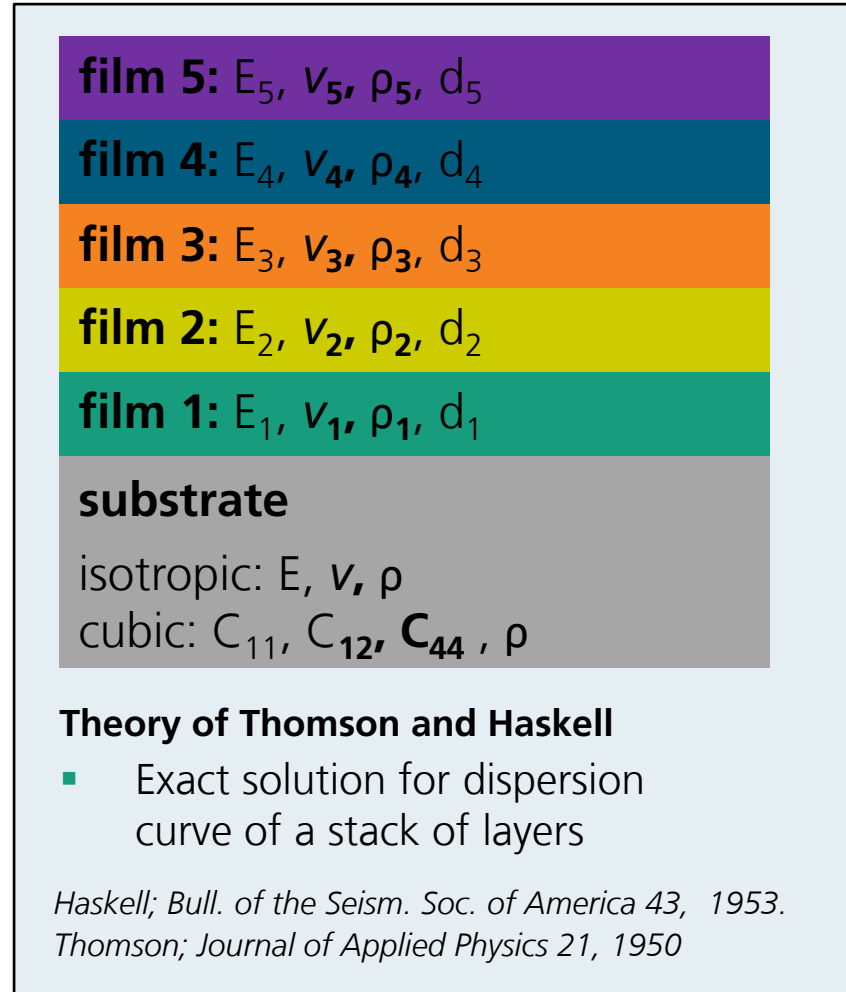
Actual influence measured on coated silicon wafer



Dispersion Curve Analysis – Multilayer Material Model

Multilayer Model by Haskell and Thomson

- Is able to model SAW propagation for any multilayer stack consisting of homogeneous layers
- 1 to 3 material parameters can be obtained from fitting data to model
- Number of material parameters that can be fitted depend on curvature of dispersion curve
- Other parameters can be derived from data bases, independent measurement or assumption



Dispersion Curve Analysis – Number of independent parameters

Material

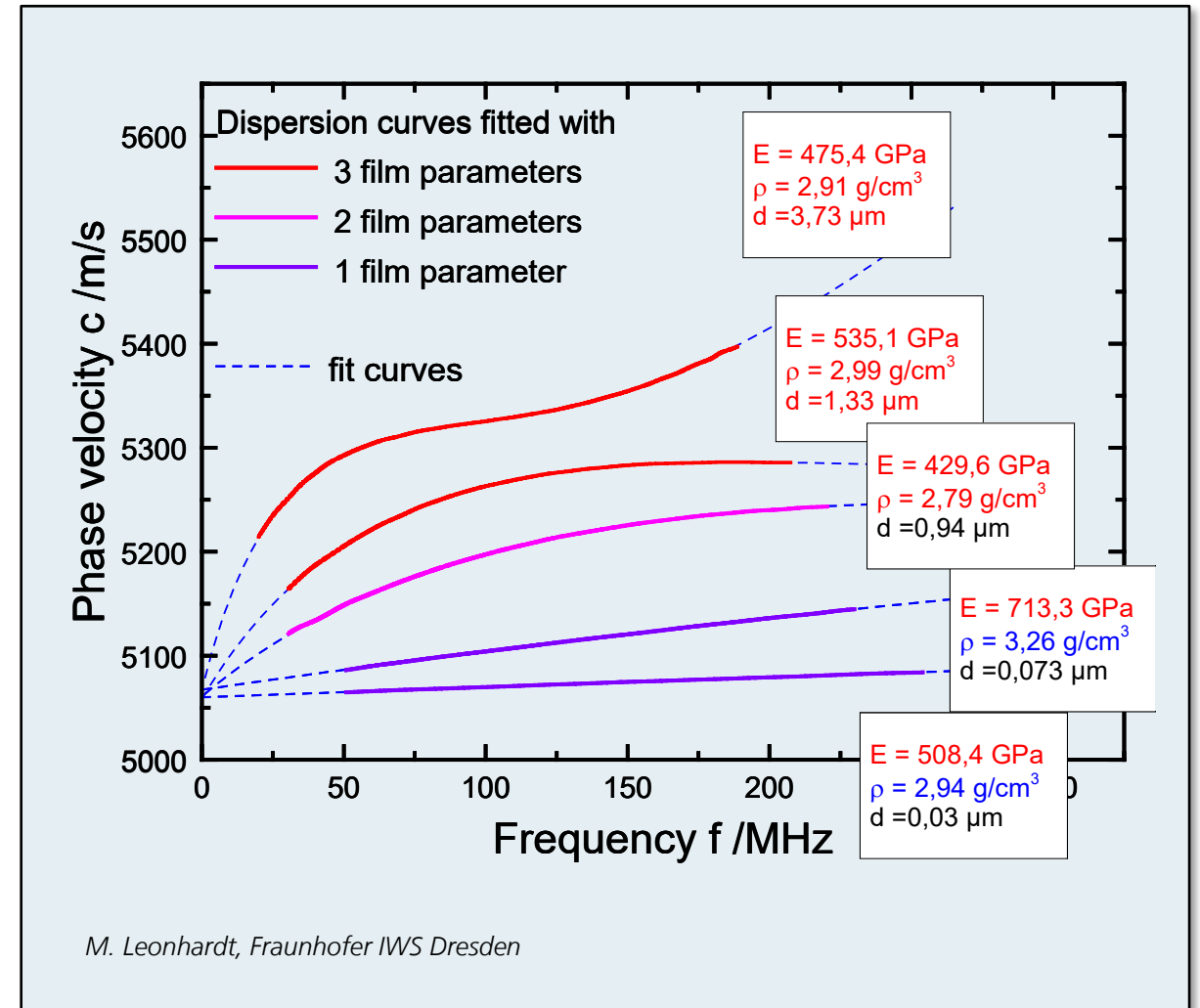
- Coating: ta-C = superhard amorphous carbon
- Substrate: Si wafer

Film parameters that can be measured

- Young's modulus E
- Density ρ
- Film thickness d

More coating parameters can be fitted for

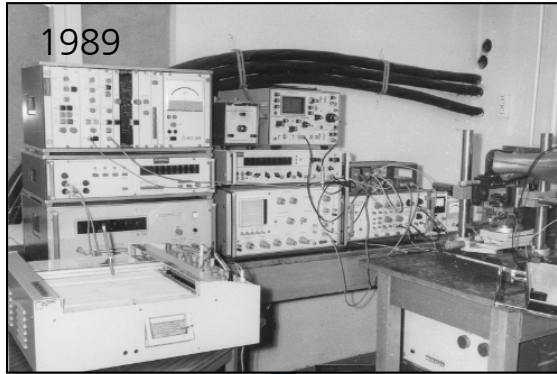
- High differences of coating and substrate
- High frequency range



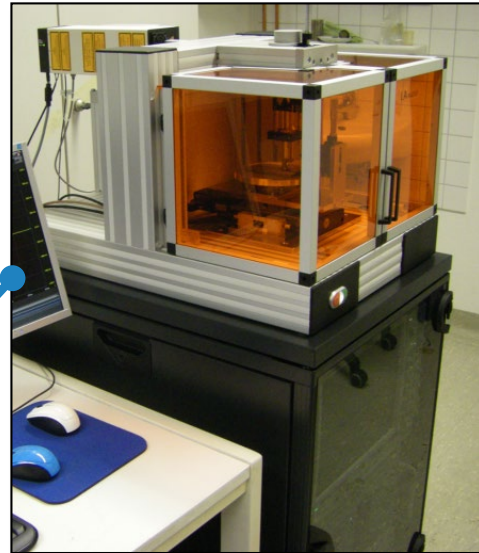


Development and Background

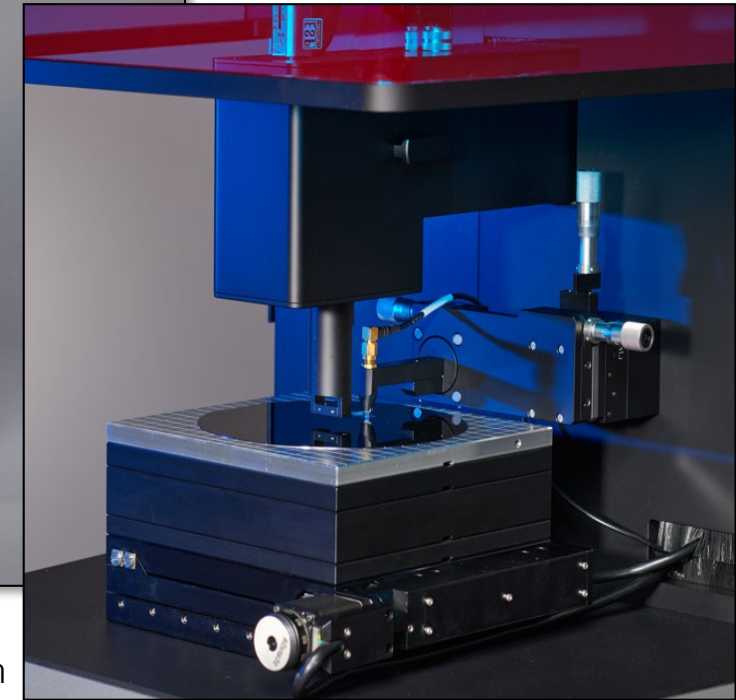
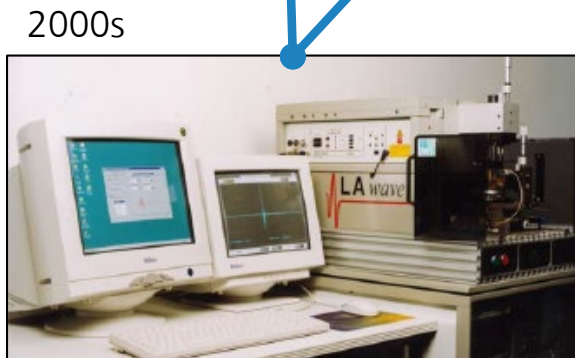
History of System Development



From 2016



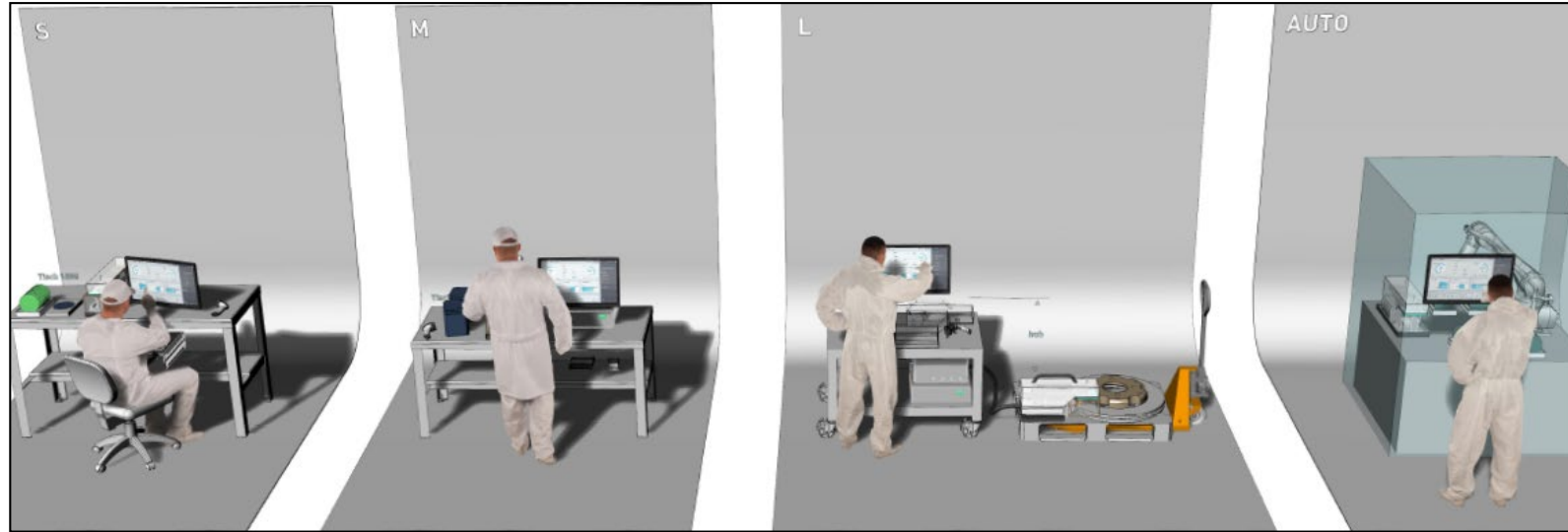
Starting 2024
New generation industry system



Current Developments

Development topics

- Quality control suitability: automated measurement and evaluation functionality
- Mobile head for robot or hand for measurement on large parts
- Measurement at elevated temperature
- Integration for customer-specific applications



Scaling concept for LWave system technology

From left to right

- Fully manual operated R&D tool
- Half-automated quality control system
- Quality control system for large components
- Fully automated quality control tool

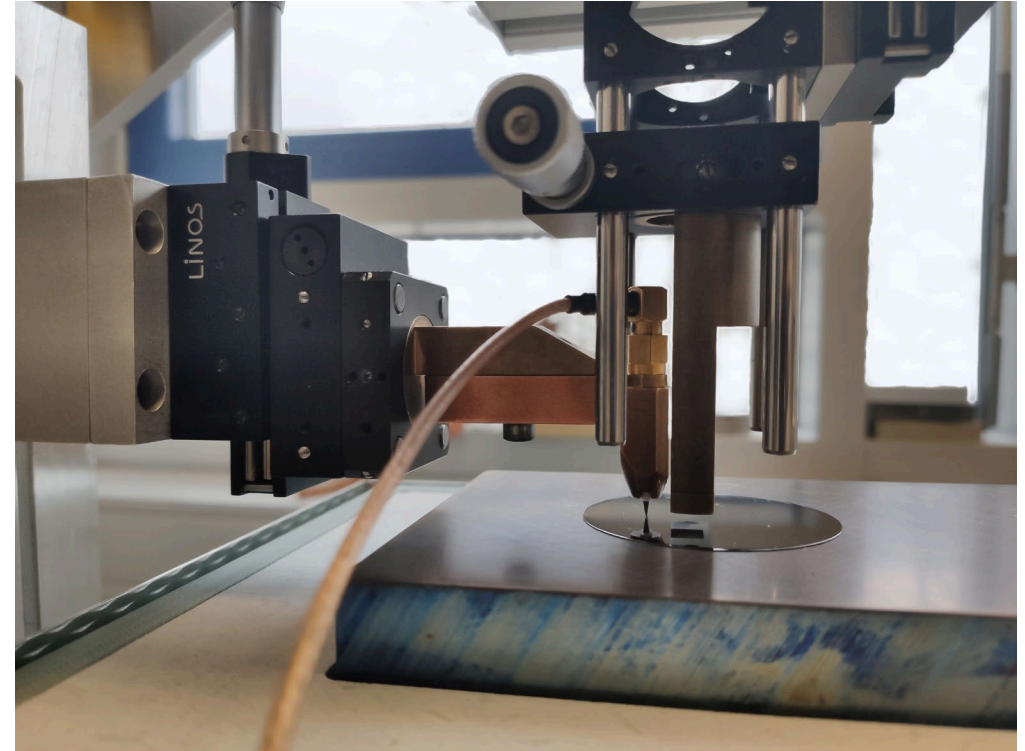
Technology Readiness

State of the art

- Standalone system, manual handling, quality control concepts - TRL 9
- 30+ systems world wide

Current development

- Automated measurement and evaluation – TRL 4
- In-situ measurement up to 600 °C – TRL 4
- Mobile head for robot or hand for measurement on large parts – TRL 4 (public funded project 2023-2026)
- Integration for customer-specific applications





Case Studies

Application - Overview

Young's modulus, thickness, density of

- All kinds of coatings: PVD, CVD, spin coating, thermal-spraying, cladding, electroplating, ...
- E.g. amorphous carbon coatings (DLC), nitrides, carbides, oxides, other ceramics
- Metal films
- Low-k films
- Polymeric sensor films
- Bulk materials, e.g. steel, brass, cemented carbide
- Si, GaAs semiconductors

Depth of

- Subsurface damage from silicon wafer processing
- Surface hardening zones e.g. after metal finishing

Case study: Very thin films < 10 nm

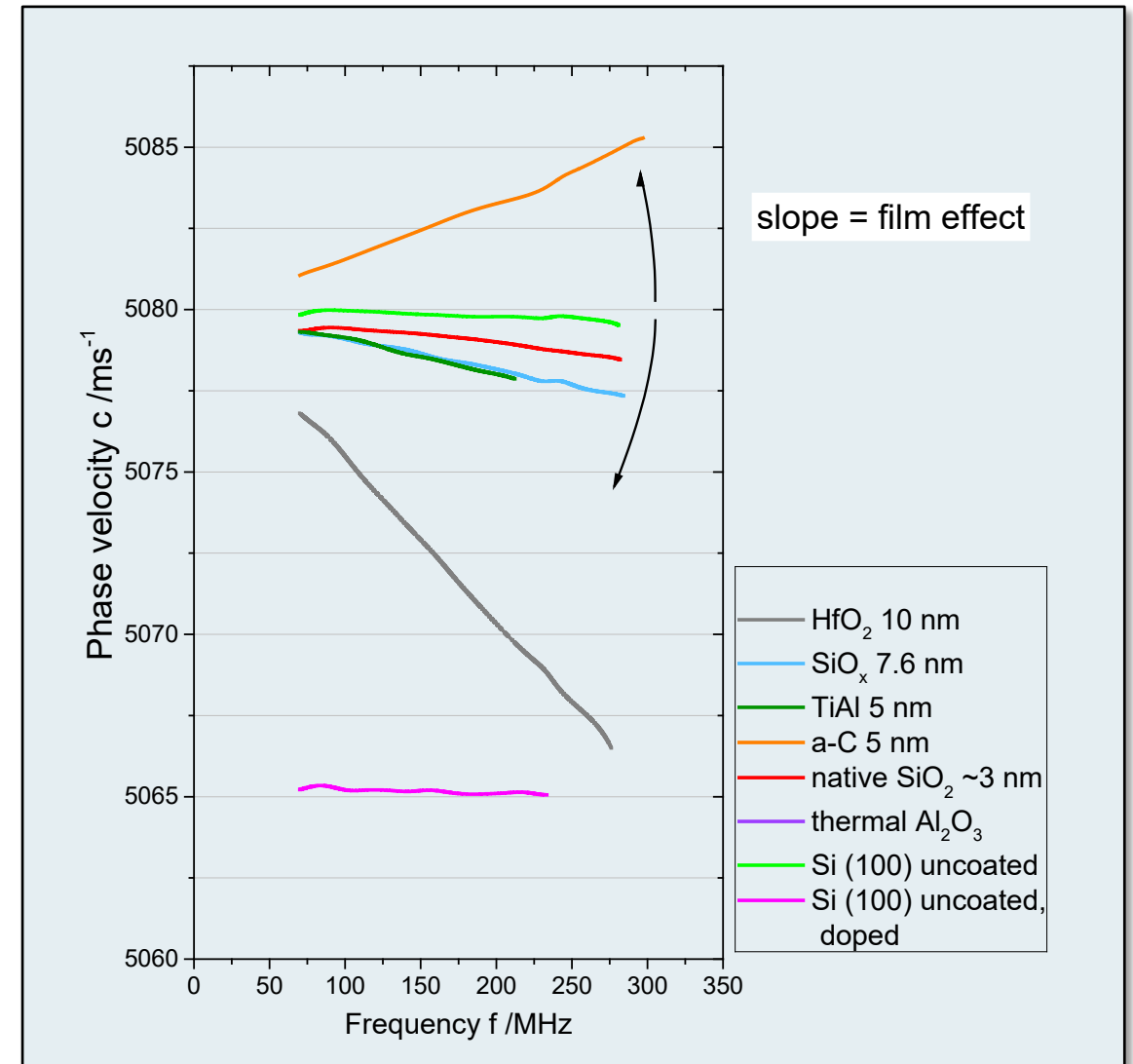
Material

- PVD coatings with thickness < 10 nm

Results

- Measurement of Young's Modulus
 - HfO₂ 220.4 GPa
 - Native SiO₂ 39.8 GPa
 - SiO_x 41.7 GPa
 - a-C 373.4 GPa
 - TiAlN 142.8 GPa
 - Silicon wafer 165.2 GPa (C11)
 - Silicon wafer (high doping) 162.9 GPa (C11)
- Measurement of thickness of Si/Al/Al₂O₃ multilayer stack
 - Thermal Al₂O₃ 3.9 nm

➔ Possibilities beyond nanoindentation



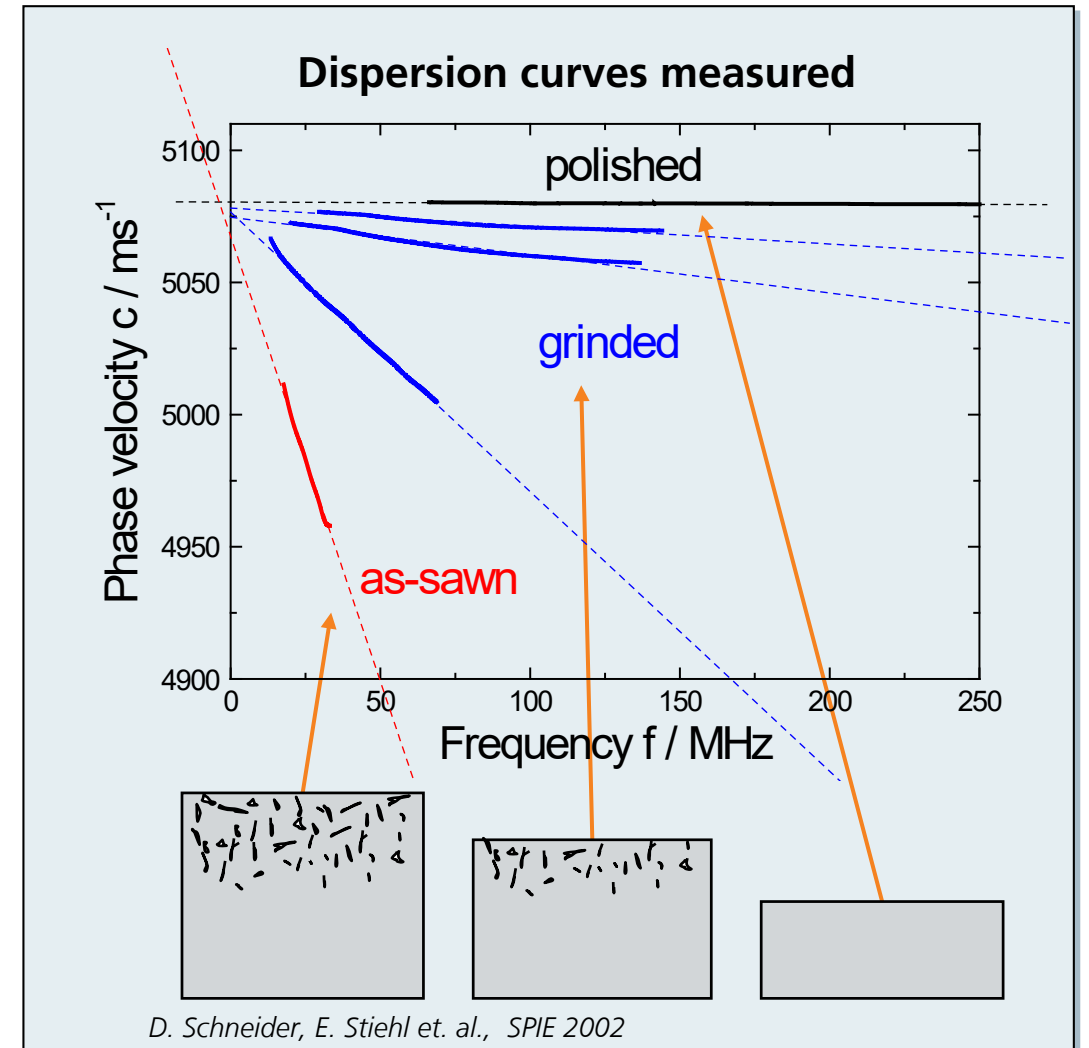
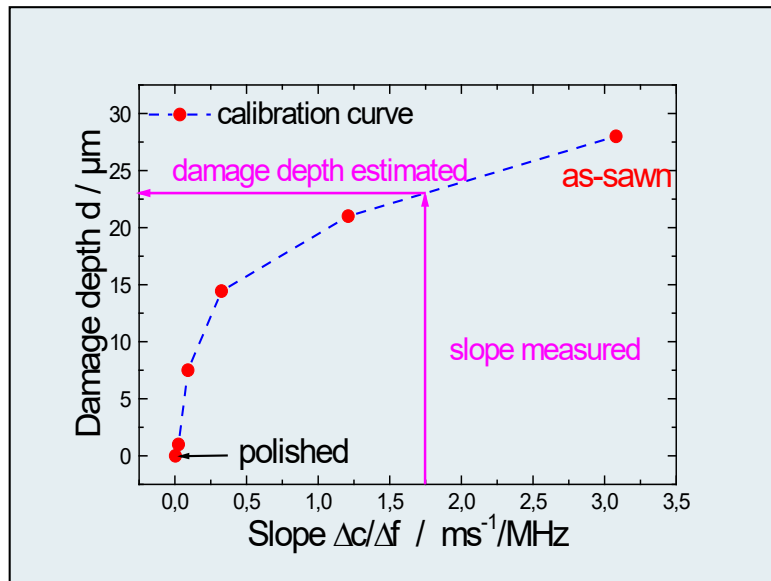
Case study: Subsurface damage in semiconductor wafers

Material

- Semi-conductor surfaces, damaged from processing

Results

- Damage layer → dispersion
- Slope = damage layer depth → allows quantification



Case study: Quality control of superhard carbon coatings

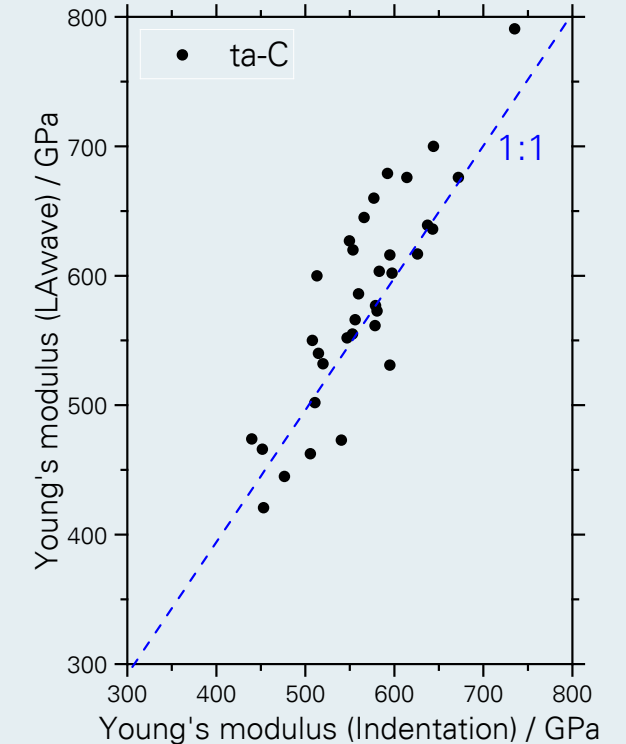
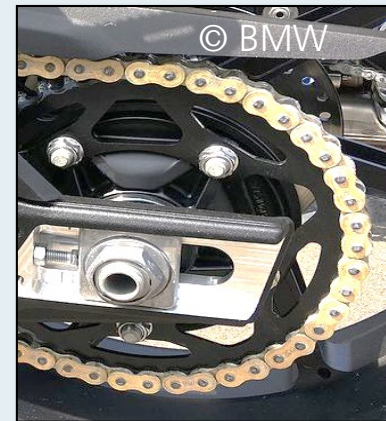
Material

- Superhard amorphous carbon coatings (ta-C, H-free DLC), hardness 40..70 GPa
- Application: Low-wear low-friction coating, e.g. piston pins in ICE, motorcycle chain
- State-of-the art: Nanoindentation → slow and error-prone technique with high indenter wear

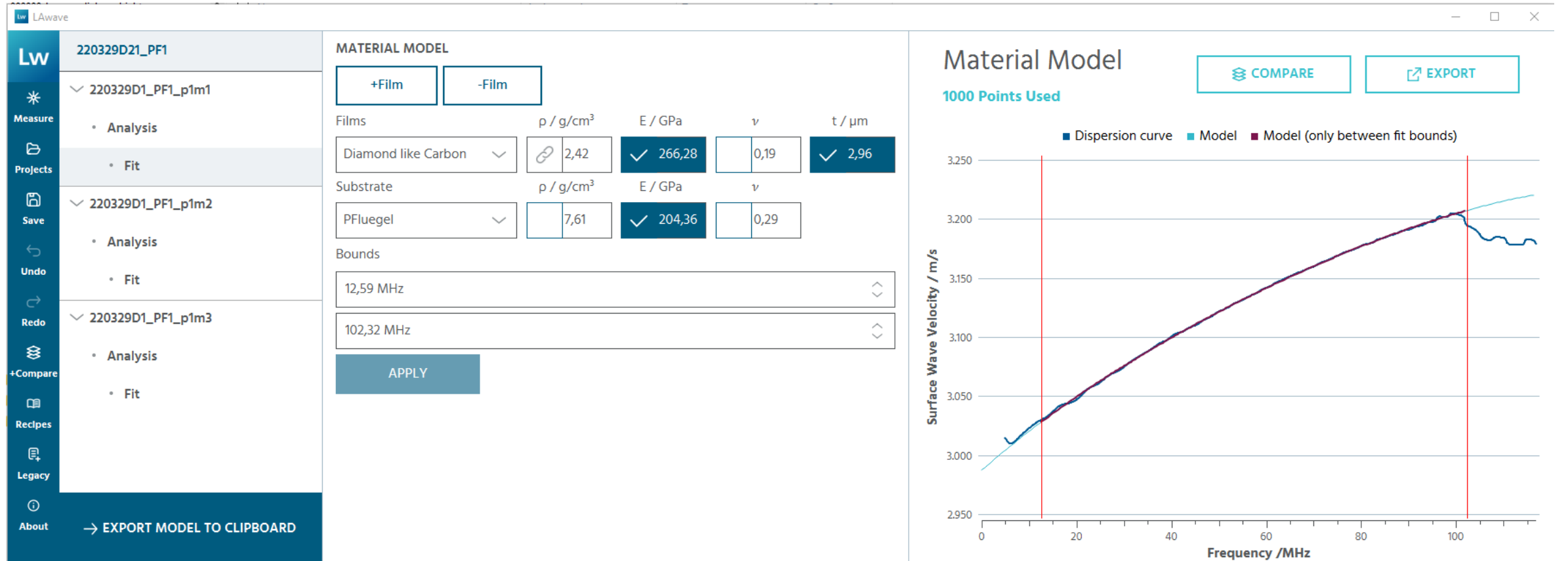
Results

- LAwave allows to access
 - Coating modulus, coating hardness
 - Coating thickness

in less than 60 seconds



Case study: Quality control of superhard carbon coatings III



Case study: Lateral cracks in SHVOF coatings

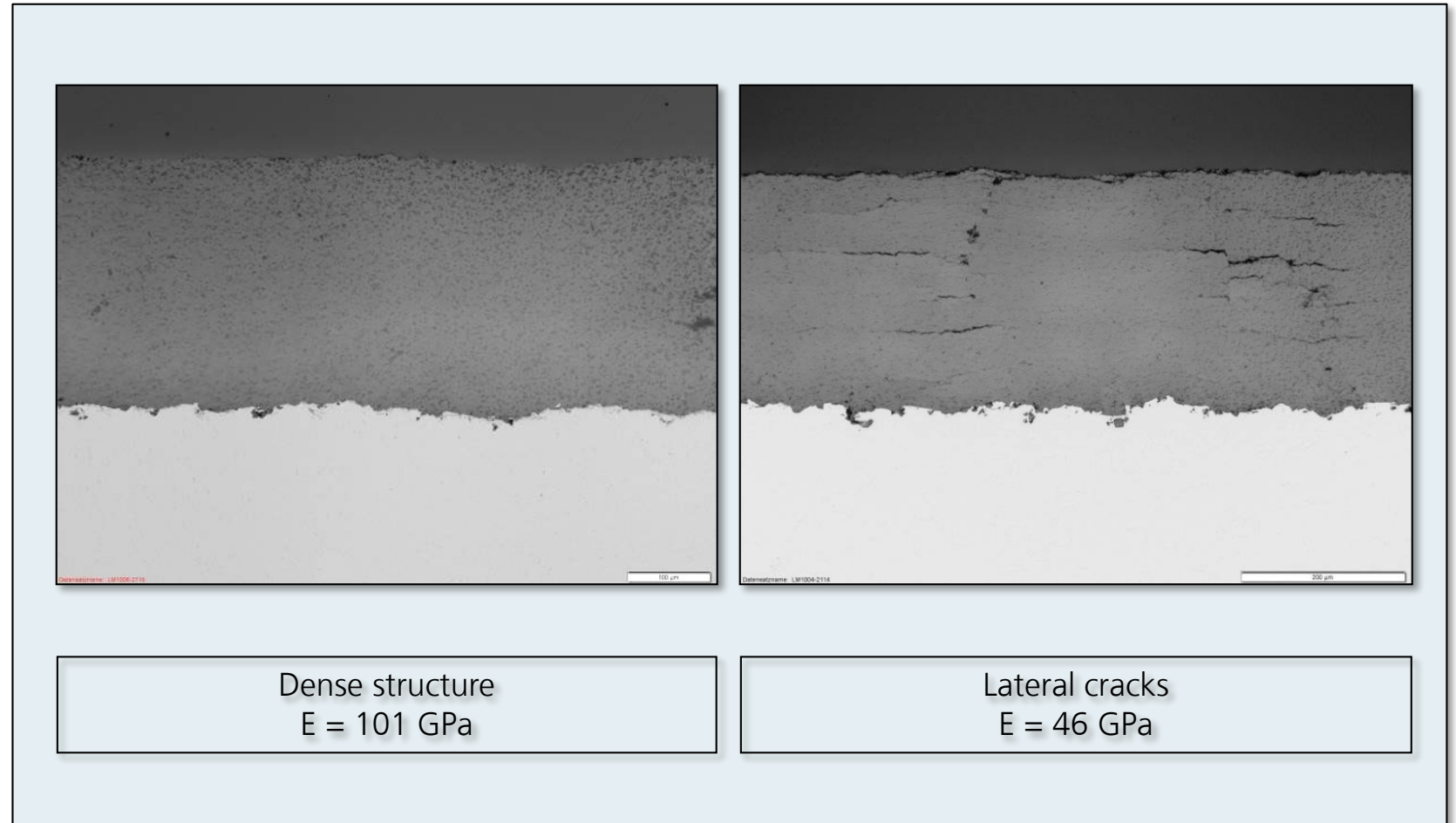
Material

- Al_2O_3 SHVOF sprayed
- Thickness around 400 μm
- Coating structure: homogenous, risk of lateral cracks

Results

- Measurement of elastic modulus
- Elastic modulus decreases due to lateral cracks

➔ **Non-destructive measurement of critical defects**



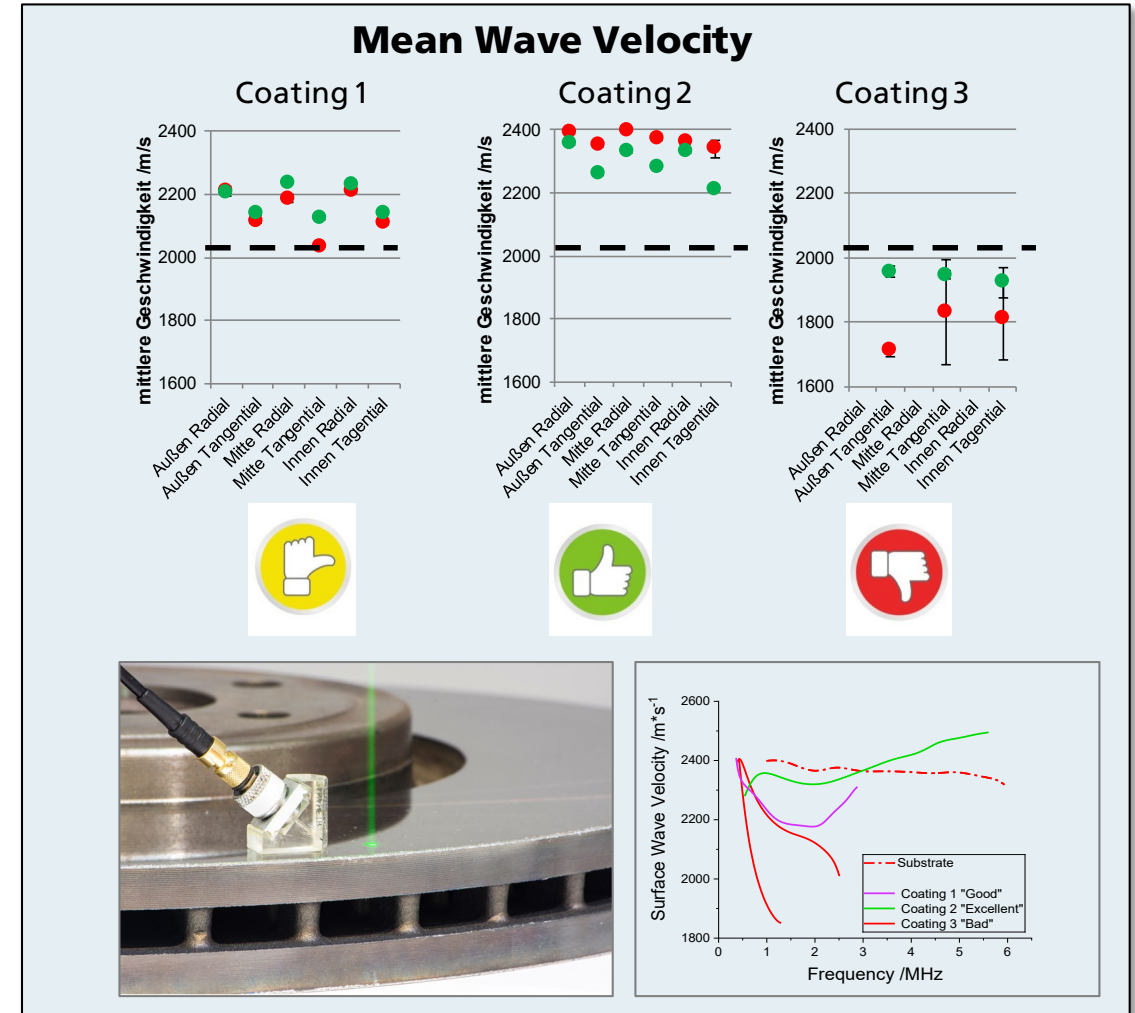
Case study: Development of novel brake disk coatings

Material

- Multilayer coatings from high speed laser cladding, carbides in Fe-based matrix
- Application: Novel brake disk coatings for high performance and e-mobility
- State-of-the-art: Cross section + SEM imaging → time consuming (~ hours... days), expensive, big infrastructure

Results

- LAwave measures mechanical key features
- Front and back, \perp and \parallel to deposition direction, anywhere on the disk
- Non-destructive (disk can be measured before and after test bench)
- six representative spots measured in less than 30 minutes



Case study: Defects in APS- Al_2O_3

Material

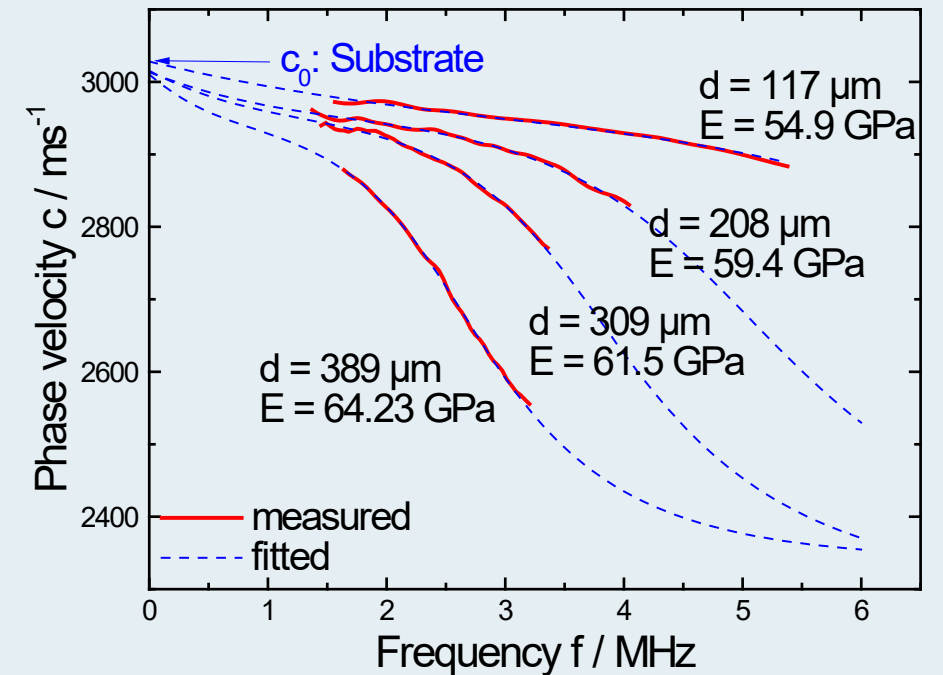
- Spray technologies: APS (or HVOF, ...)
- Al_2O_3 (or Cr_2O_3 , TiO_2 , ...)
- Thickness 100 to 600 μm
- High roughness $R_a > 1 \mu\text{m}$
- Coating structure: micro-cracks and porosity

Results

- LAwave measurement gives coating thickness and effective elastic modulus E
 - Effective elastic modulus varies due to different crack and pore density
- ➔ **Quality and mechanical behavior of coating can be measured non-destructively**

Al_2O_3 (APS) on steel

E (tabulated; compact material) = 350 GPa

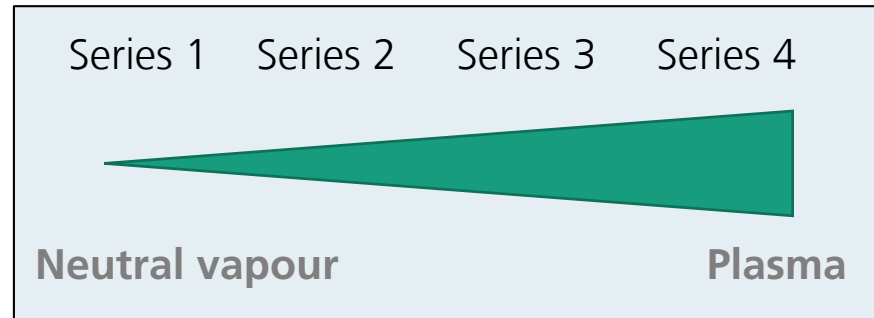


L.-M. Berger et. al.: VIP-Journal Vol. 24, 2012

Case study: Pores in metal films (1/2)

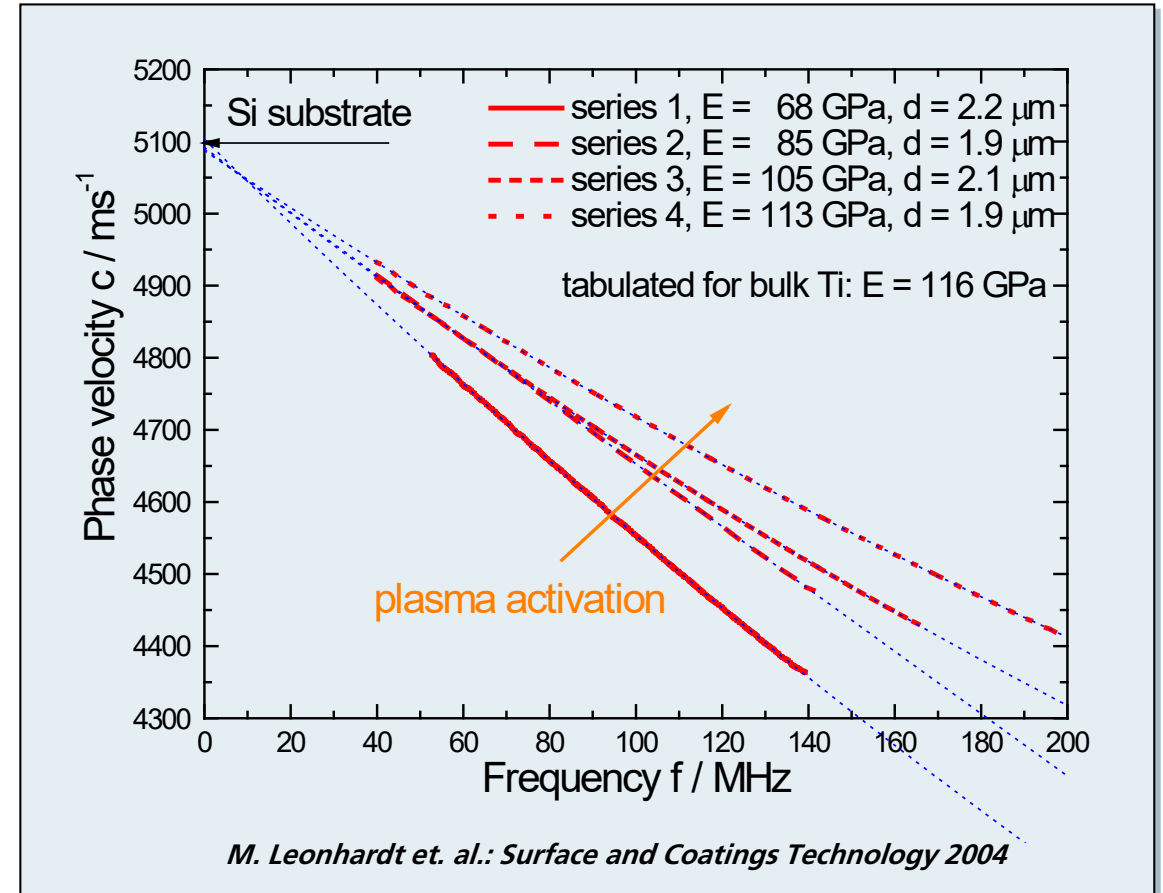
Material

- 2 μm Titanium coating on Si wafer
- PVD: Electron beam evaporator + additional plasma activation

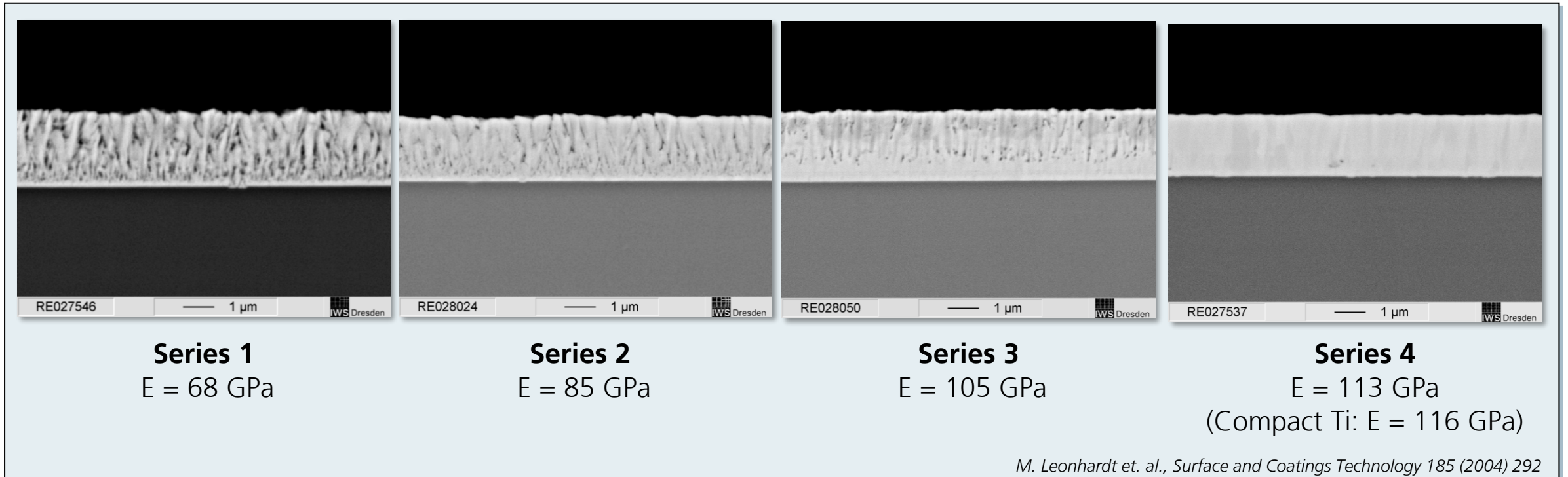


Results

- Effective Young's Modulus is measure of porosity
- No activation \rightarrow porous films ($E = 68 \text{ GPa}$)
- High activation \rightarrow dense films ($E = 113 \text{ GPa}$)



Example: Pores in metal films (2/2)



➔ Effective Young's Modulus strongly correlates with porosity observed in SEM cross section

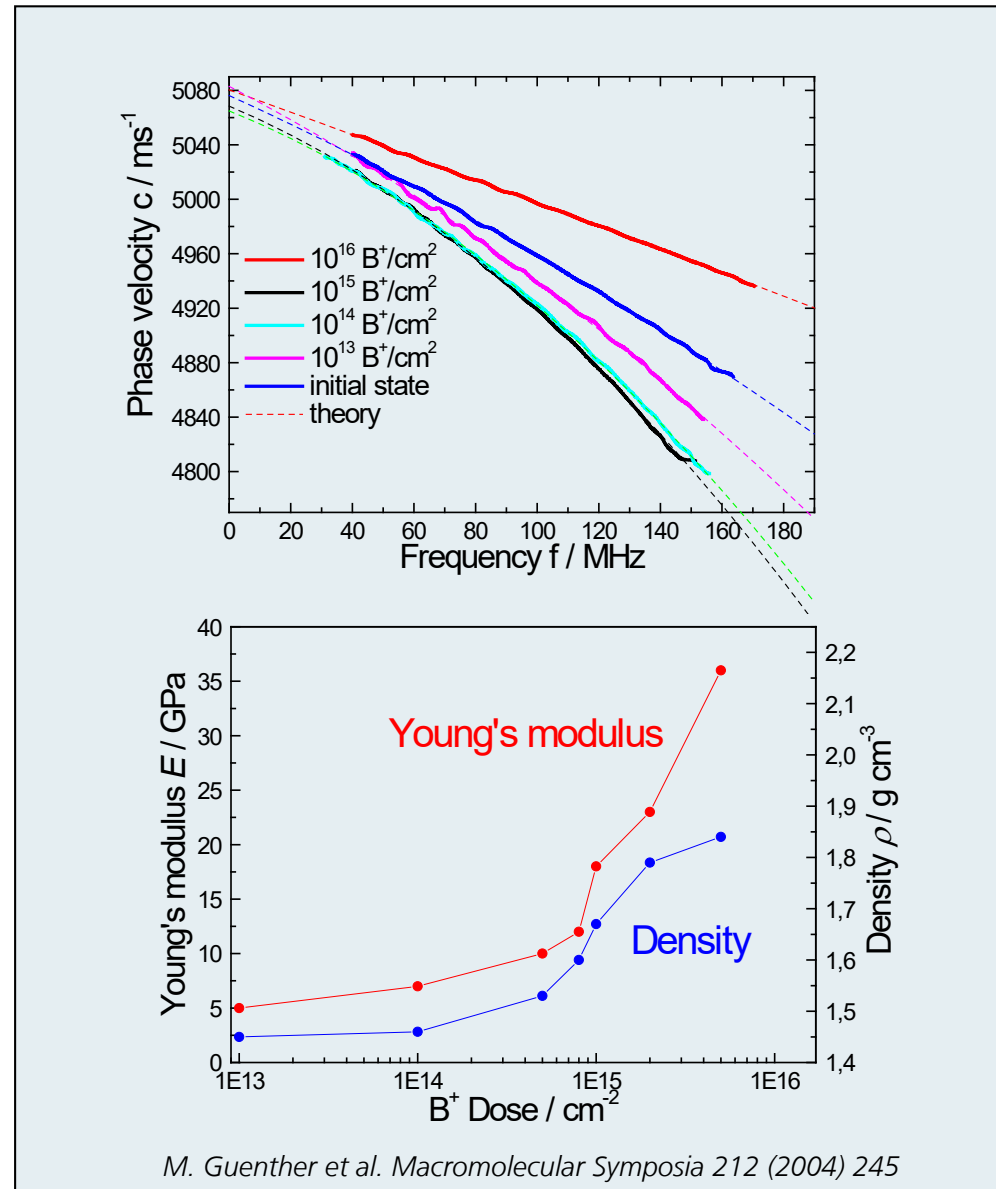
Case study: Polymeric sensor films

Material

- Polyimide films on silicon wafer for humidity sensors
- Film thickness 500 to 600 nm
- B⁺ ion implantation to improve sensor properties

Results

- Young's modulus E and Density ρ were obtained from the measurement
- Density and Young's modulus increase with B⁺ dose
- Distinct effect for a B⁺ dose $> 10^{15}$ B⁺/cm²
- Young's modulus increased by approx. 700 %



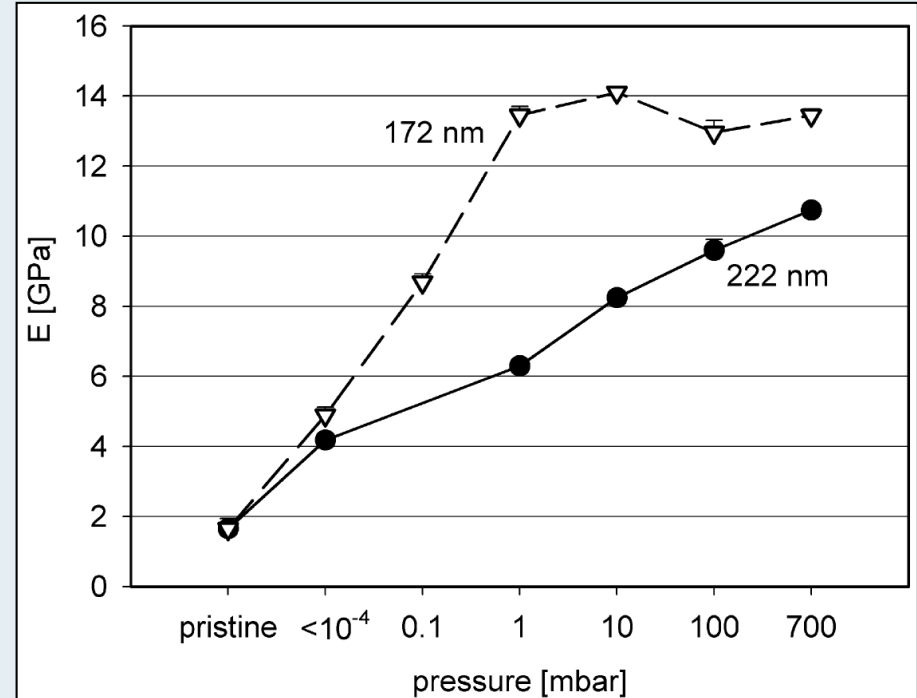
Example: Porous low-k films

Material

- Nano-porous SiCOH low-k films
- High porosity: > 40 %
- Rel. permittivity $k < 2.5$
- Minimum required stiffness $E > 5$ GPa

Results

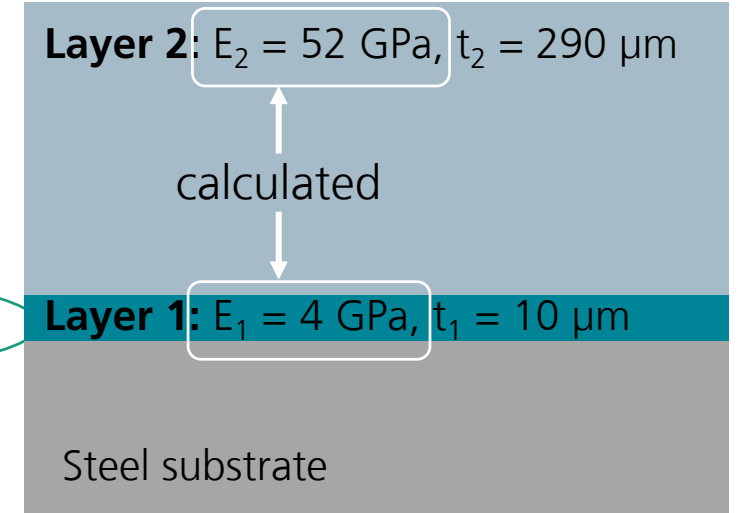
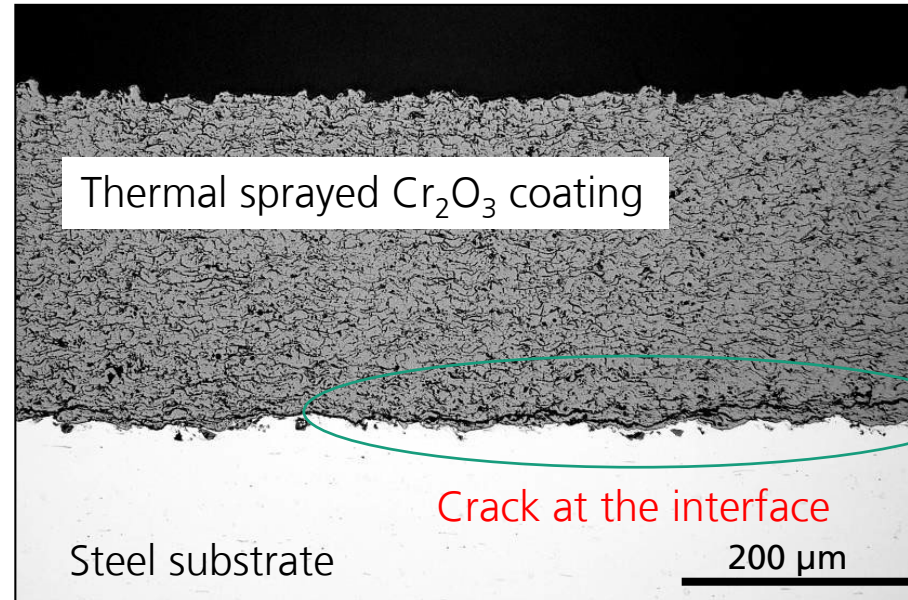
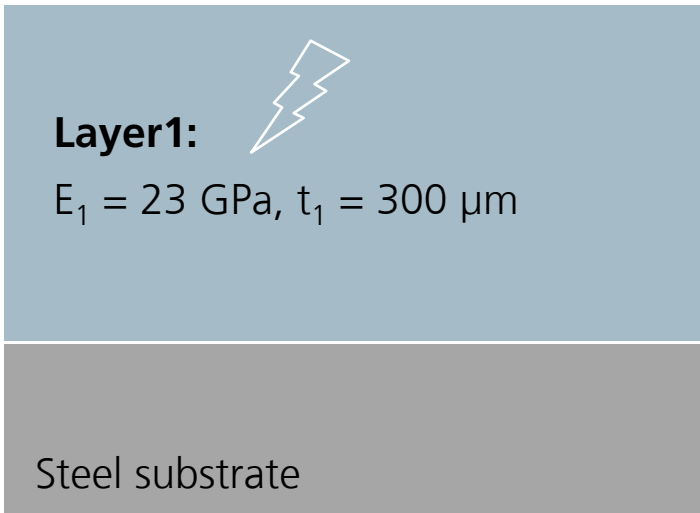
- Young's modulus and density can be measured
- Higher reliability than results from nanoindentation



Irradiation with 172 nm and 222 nm photons, $\rho = 1.2$ gcm^{-3} and $d = 200$ nm

Prager et al. Microelectronic Engineering 85 (2008) 2094–2097

Case study: Delaminations



1st step: simple 1-layer model

- Measured Young's modulus smaller than expected ($E = 50 \text{ GPa}$)
- Measurement and model do not fit

2nd step: cross section preparation

- Delamination revealed at interface

3rd step: 2-layer model

- 2-layer model fits expectation when weak interface is assumed

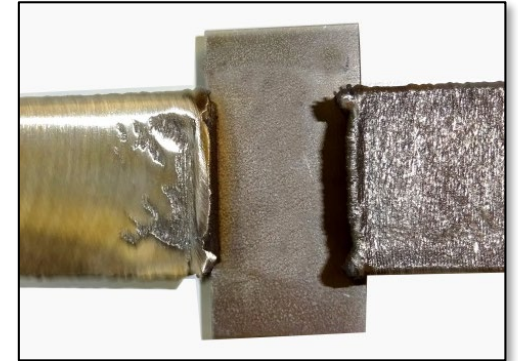
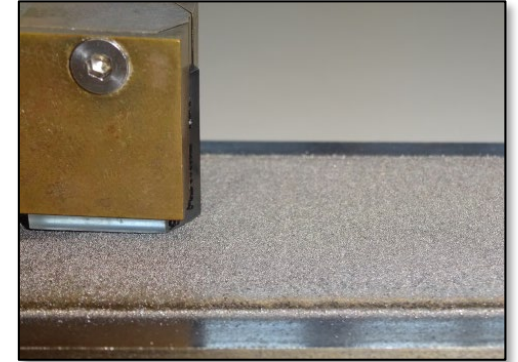
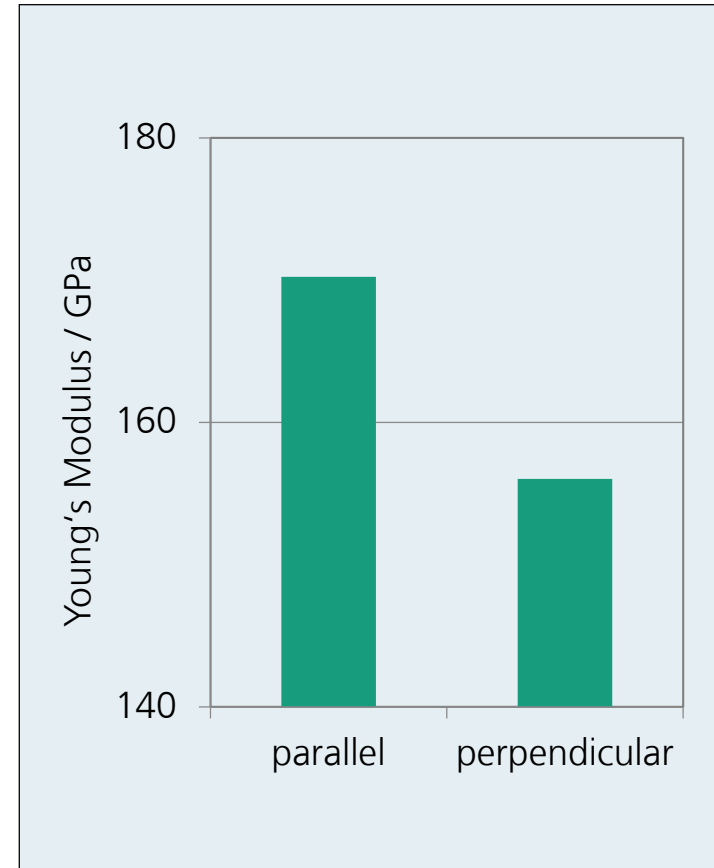
Case study: Laser cladding, laser buildup welding

Material

- Coatings from Laser Cladding on steel, thickness: 0,5 ... 2 mm
- Bulk samples from Laser Buildup Welding
- e.g. Inconel 625, 316 L
- High roughness $R_a > 1 \mu\text{m}$

Results

- Young's Modulus from measurement
- Influence of buildup direction (\perp or \parallel to cladding lines)
- Microstructure: Influence of cracks and porosity



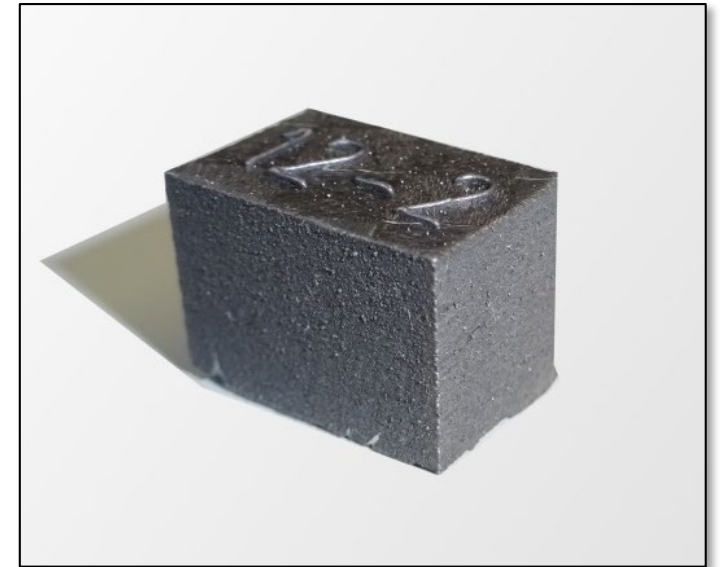
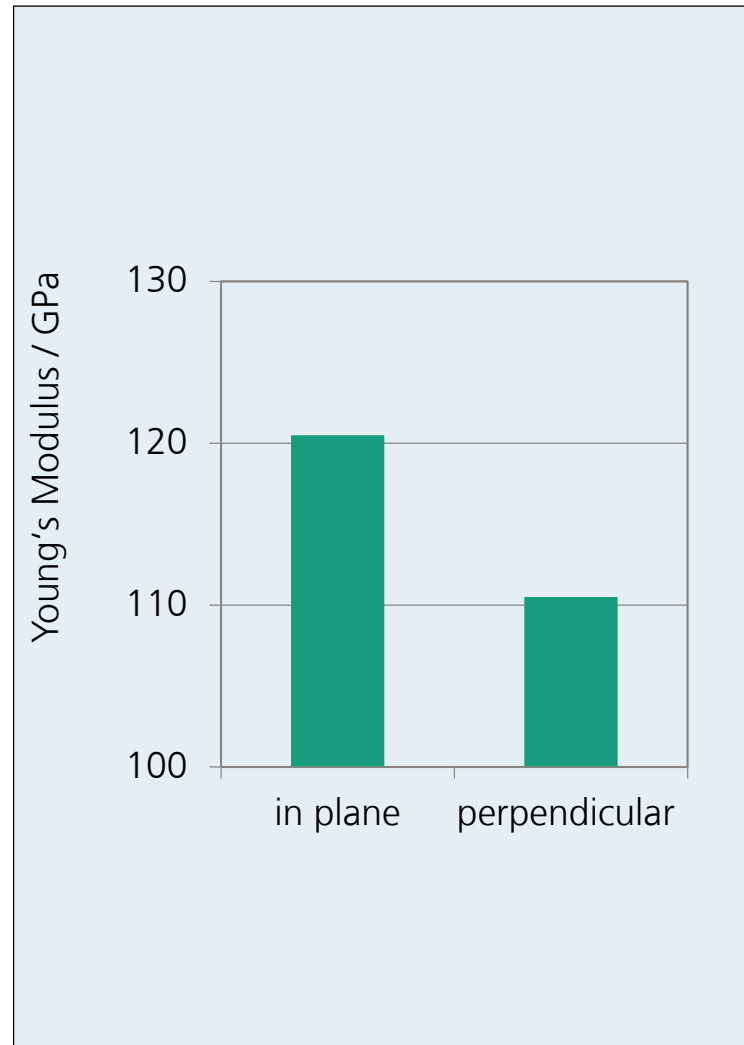
Case study: Parts generated from Selective Laser Melting (SLM)

Material

- Parts generated by selective laser melting
- Material: e.g. AlSi40, Ti6Al4V, ...

Results

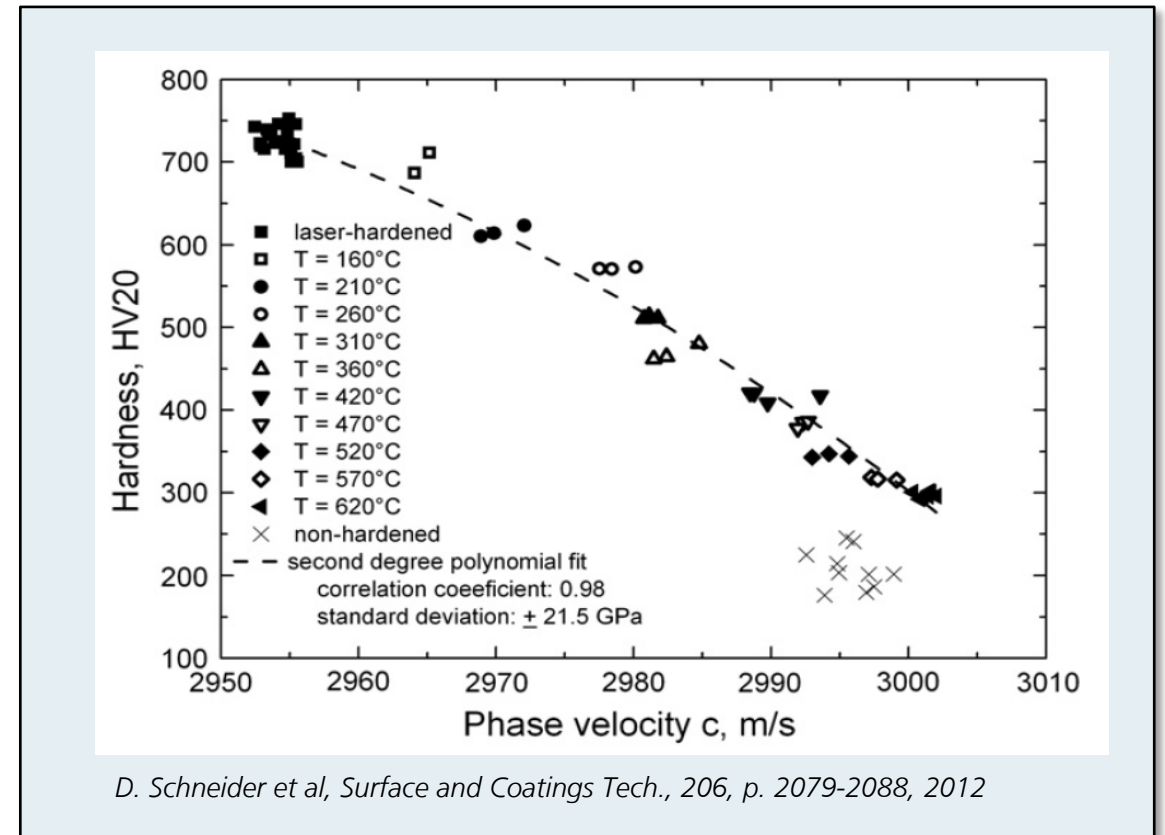
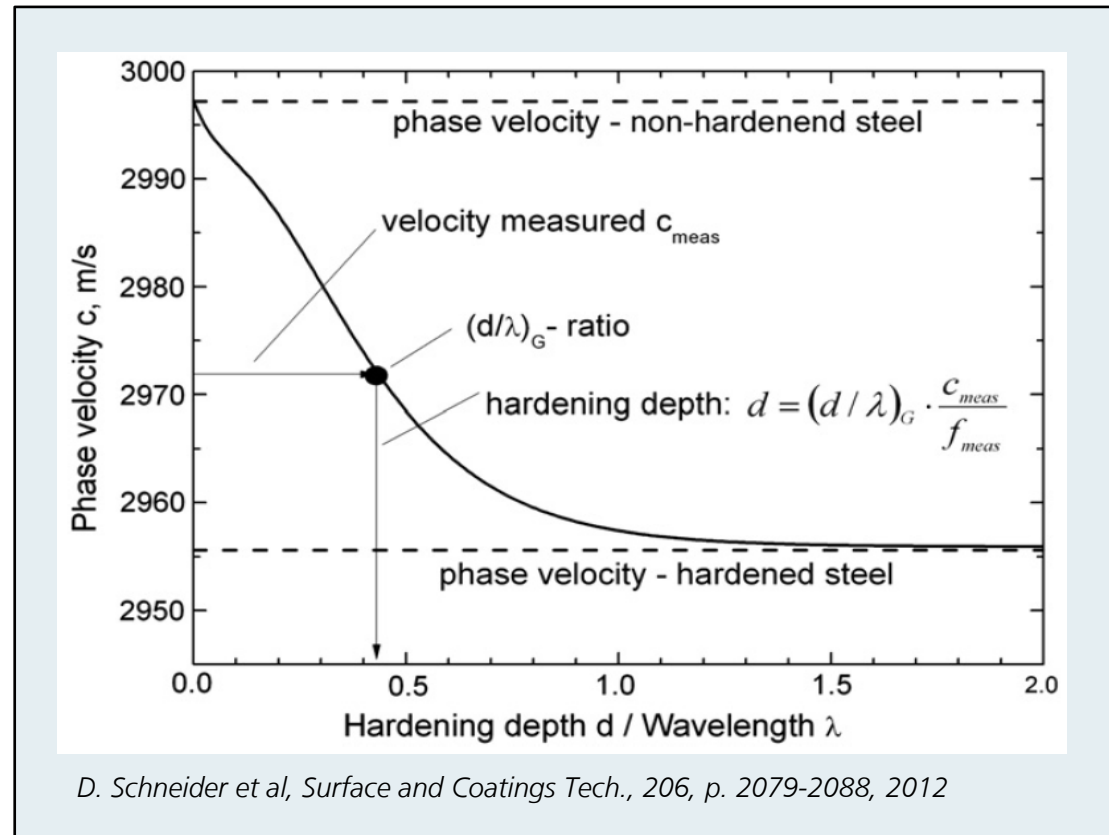
- Young's modulus
- Influence of buildup direction (\perp or \parallel to built up lines)
- Microstructure: Influence of cracks and porosity



Case study: Hardening depth

Material: Surface hardened metal (case hardening, laser hardening, nitrogen hardening, ...)

Results: Hardening depth, surface hardness



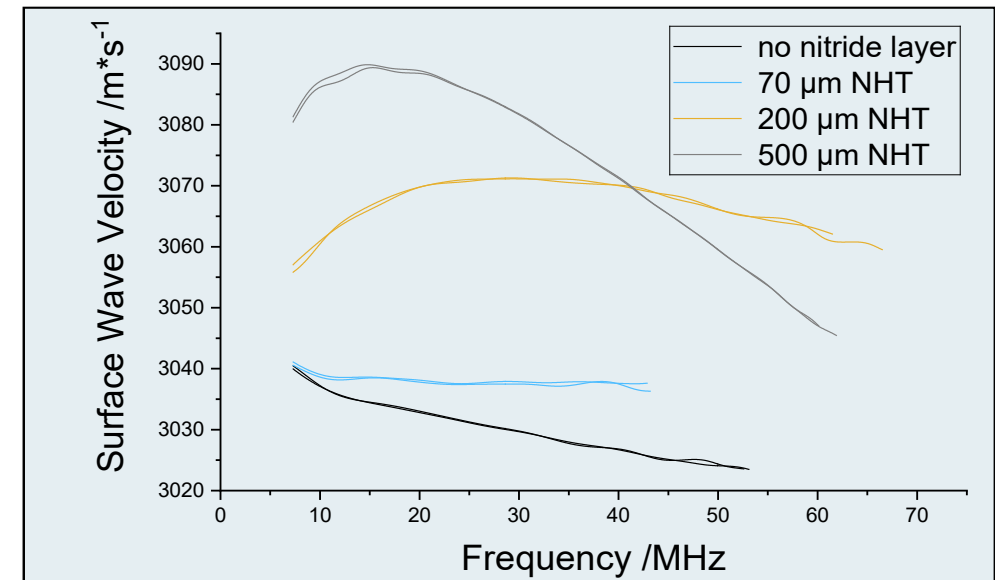
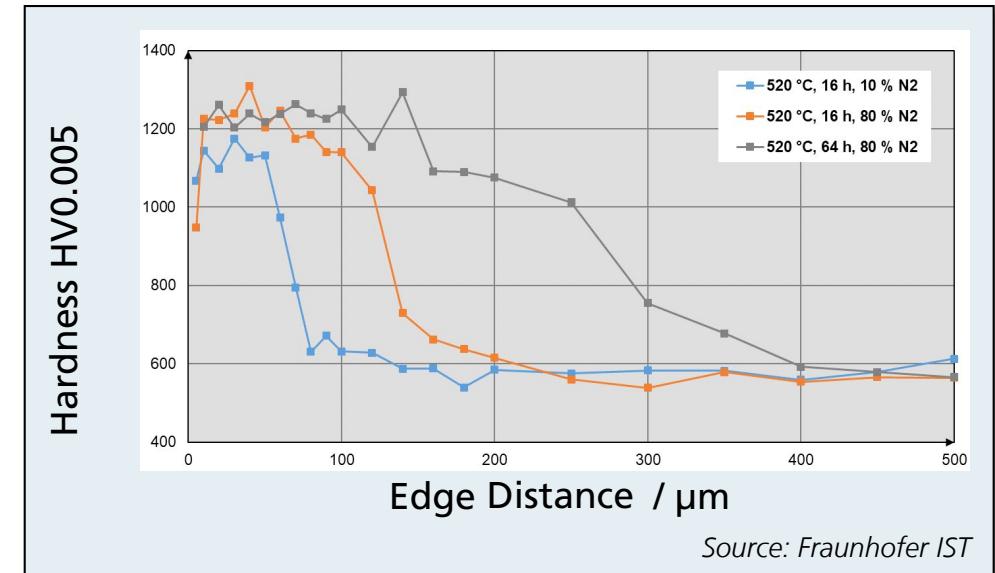
Case study: Nitriding depth

Material

- Steel 1.2343
- Nitrided with different nitride hardening depths (= NHT)

Results

- Strong correlation between hardness profile and dispersion curves
- Dispersion curves hold information about NHT, surface and core hardness, and more





Methodical Aspects

Measurement on native rough surfaces

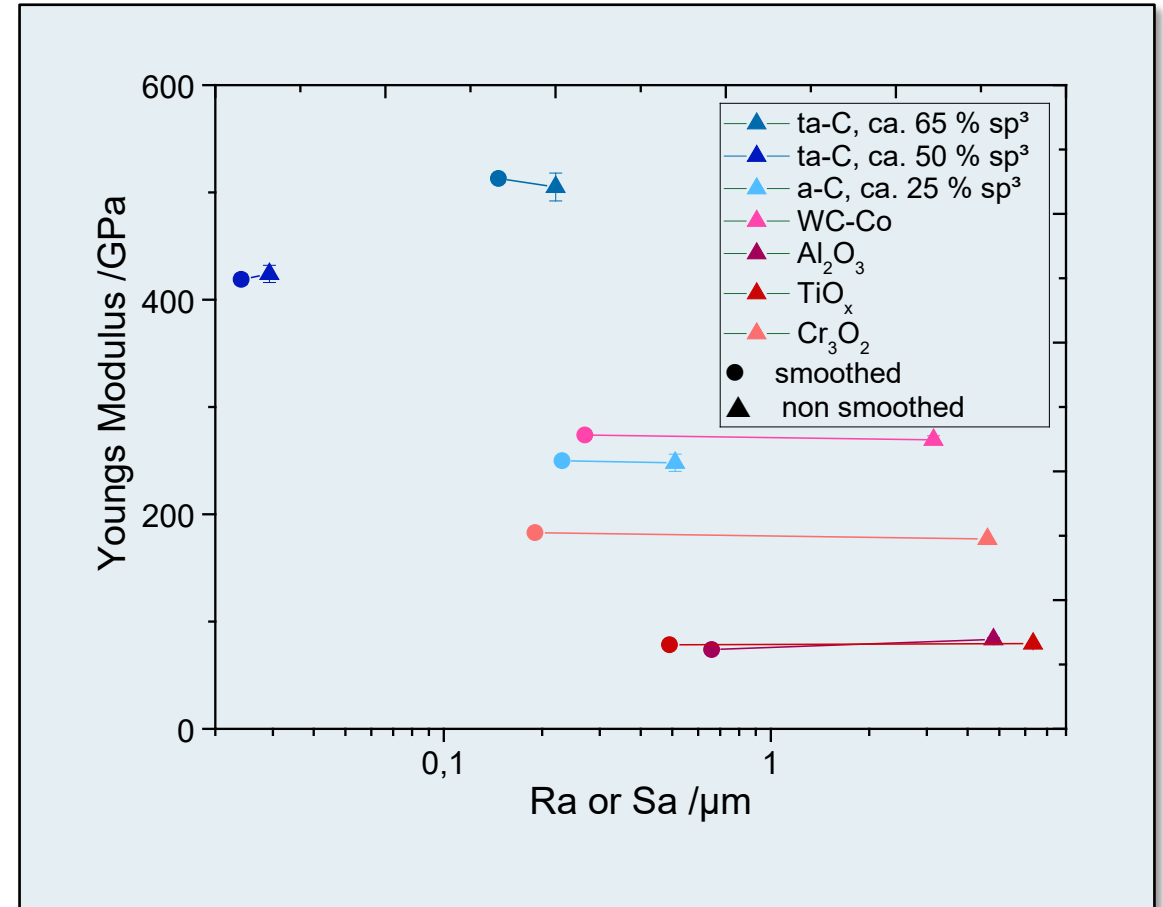
Material

- Various hard PVD and thermal spray coatings
- Surfaces both as-deposited and smoothed

Results

- Measurement on both surfaces conditions possible
- Young's Modulus does not change
- Condition: Roughness (R_a 0,02 - 6,5 μm) \ll wave length (ca. 50 μm @ 60 MHz)

➔ **Measurement on native rough surfaces as reliable as on smooth surfaces**



Influence of sample curvature

Measurement in axial direction

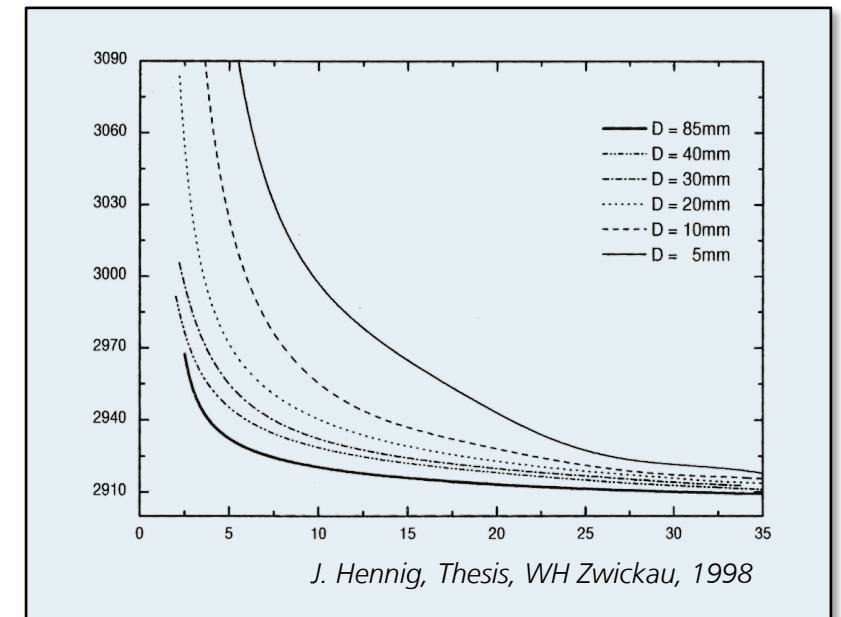
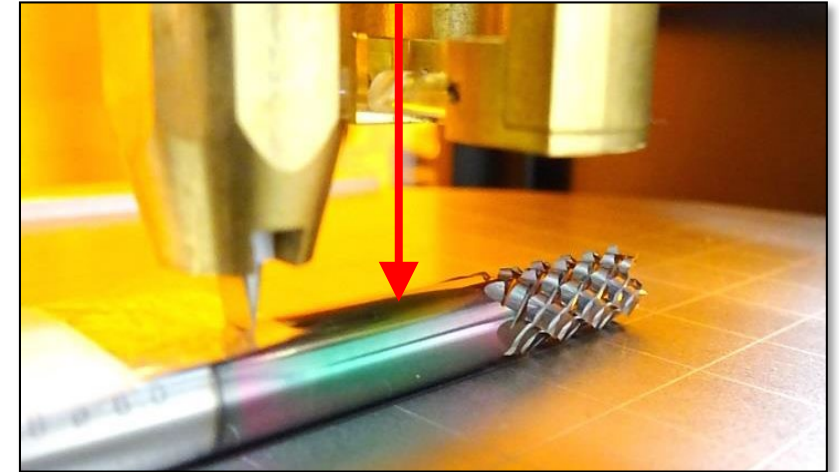
- No limitations from curvature
- Signal/noise ratio smaller

Measurement in radial direction

- Additional dispersion from curvature at low frequencies
- Correction of the influence of curvature mathematically possible

➔ No general limitations from sample curvature

➔ Practical limitations for complex 3D structures



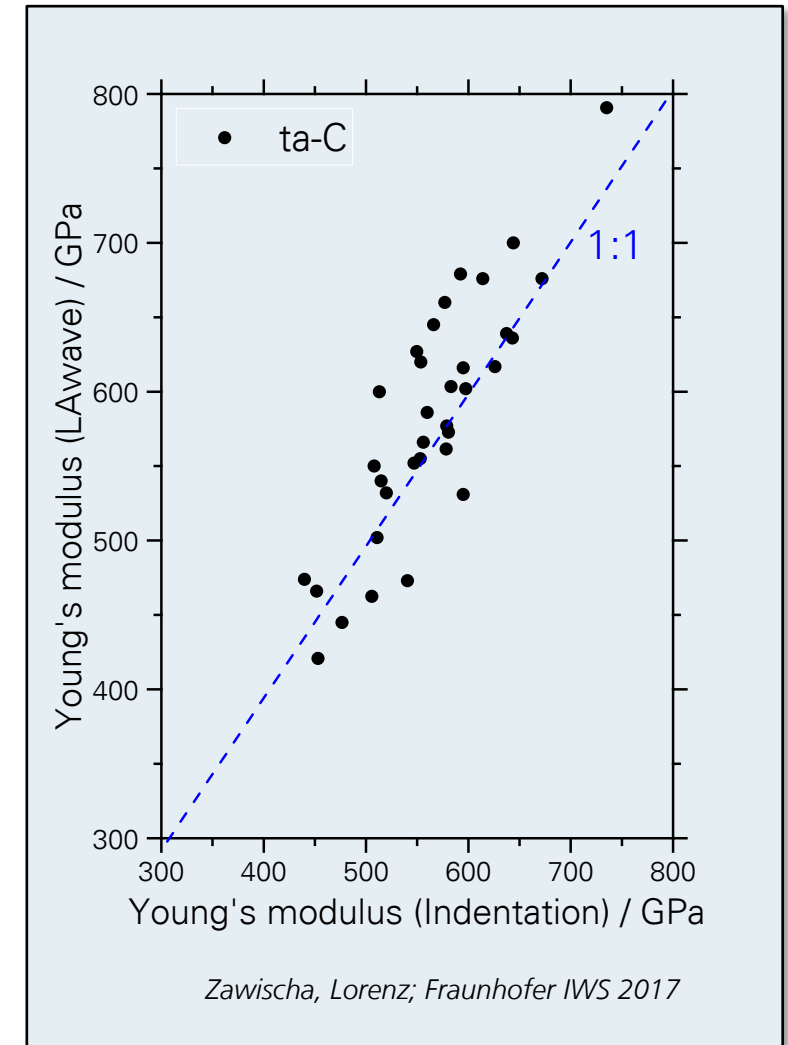
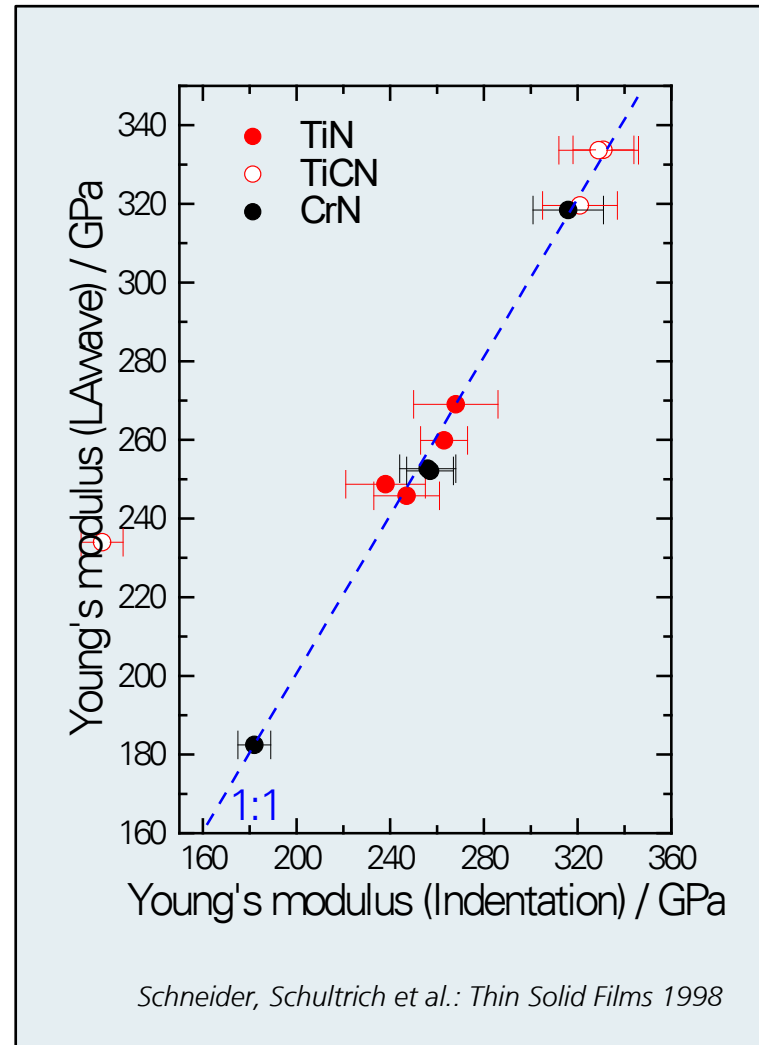
Comparison with instrumented indentation testing

Coating Materials

- TiN, TiCN, CrN (magnetron sputtering)
- ta-C (LaserArc)
- Film thickness: $d > 1 \mu\text{m}$

Result

- Excellent agreement of Young's Modulus from both methods for solid, non-porous bulk materials



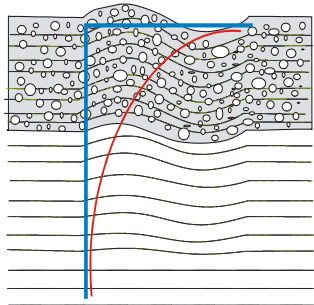
Comparison with instrumented indentation testing

Coating Materials

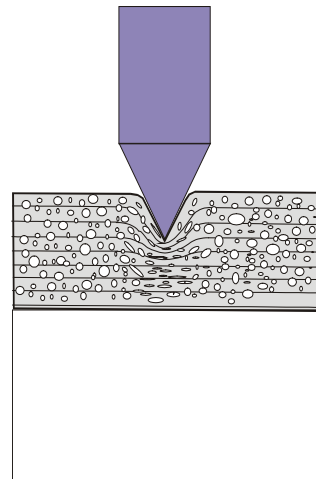
- Porous low-k films

Result

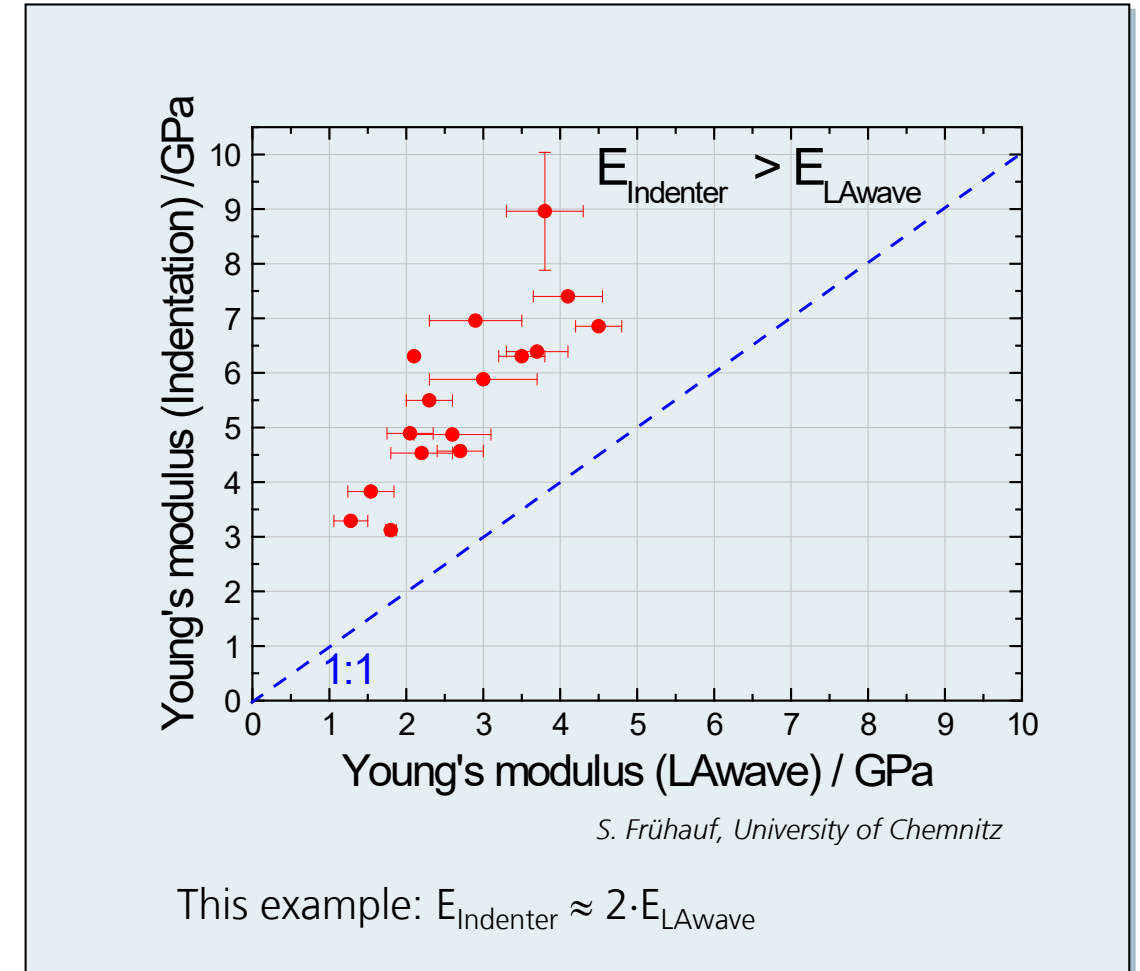
- Effective modulus is strongly overestimated with indentation due to compressed pores



Surface acoustic waves
Reversible deformation
→ True elasticity



Indentation
Densification of microdefects
→ Distorted results



Comparison with instrumented indentation testing (nanoindentation)

	LWave	Nanoindentation
Method	Dynamic: Sound velocity $c \sim \sqrt{(E/\rho)}$	Quasi-static: $E_r \sim dP/dh$
Measuring area	> 5 x 5 mm ² (integral method)	< 10 μm ² (local method)
Measuring time	One minute	~ 1 hour (including sample preparation and calibration)
Minimal film thickness	A few nanometers	≈ 100 nanometers
Surface roughness	No requirements	Smooth surface necessary
Difficult material systems	Transparent and high damping materials	Soft and superhard materials, very thin coatings

➔ **LWave method has superior benefits over nanoindentation for many application scenarios**

Limits

Method will not work

- If surface (coating or substrate) does not absorb laser light → no wave generated
- Substrate is too thin → plate waves instead surface waves
- Damping is too high → polymers, very high roughness, very high crack density

Challenging

- On curved surfaces
- On very small areas
- Complex coating architectures, gradient (limited quantification)

LWave around the world

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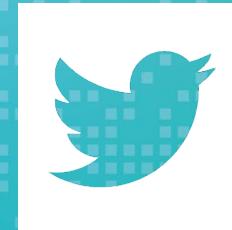
Image: Aris Katsaris CC BY-SA 3.0

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